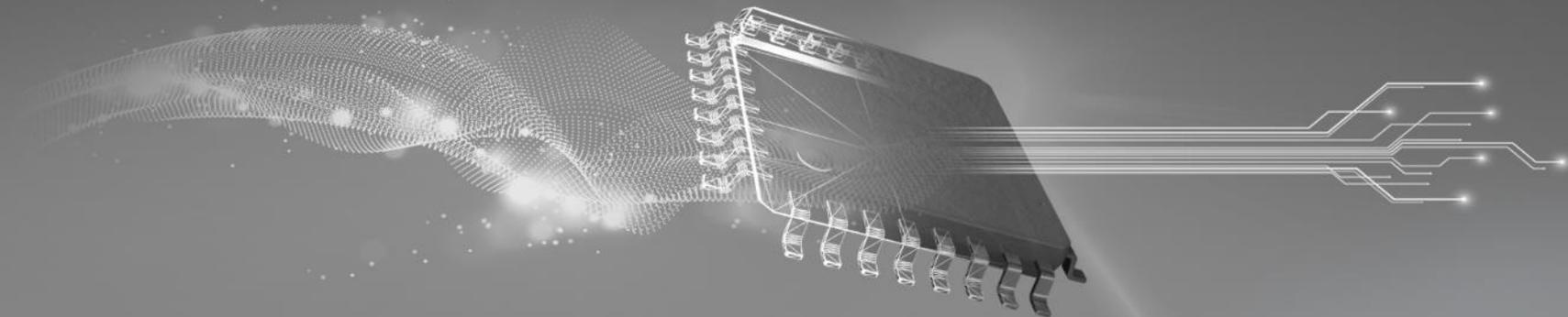


# TI TECH DAYS



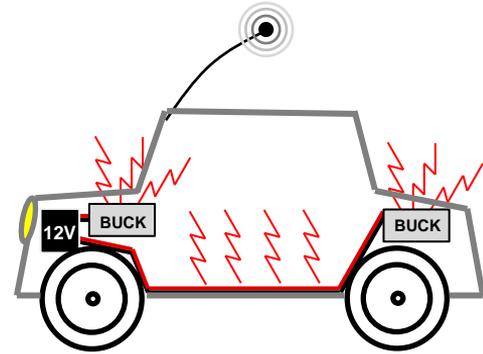
## Practical Buck EMI Debugging for Automotive Applications

Sam Jaffe

Texas Instruments

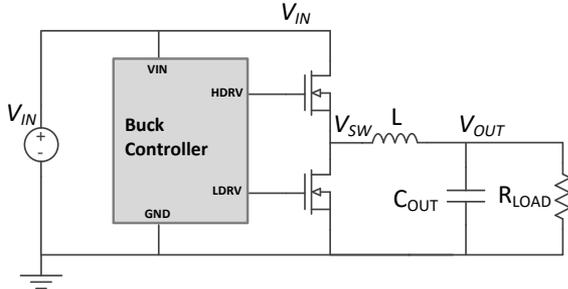
# Agenda

- What is EMI?
  - Why do we need to pass EMI?
  - How do we measure EMI?
- How to achieve great EMI performance
  - Layout guidelines, part selection, part features.
- Tests and debugging
  - Quick checks.
  - Could fix the problem without changing schematic/layout!



# What is EMI – a buck's perspective

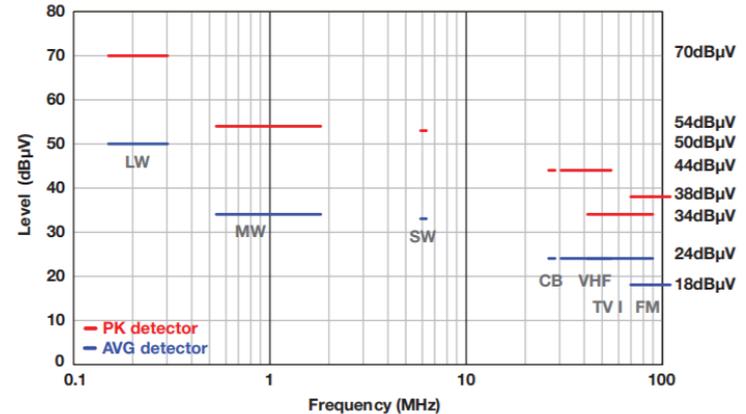
- EMI = electromagnetic interference
- Bucks generate noise:
  - Input ripple, coupling to nearby circuits, electromagnetic radiation.



- Other components can be sensitive to noise:
  - AM broadcast 150 kHz → 30 MHz
  - AM radio 30 kHz → 1.8 MHz
  - FM radio 76 MHz → 108 MHz and more

**Too much interference degrades or prevents proper system operation.**

We have standards to tell us how much we can emit without greatly affecting other systems.



Conducted EMI limits - CISPR25 class 5

# Filtering

# Filtering – Typical components in order of importance

## 5. CM Choke

### Common-mode choke

Blocks common-mode current. Very effective but expensive. This is the most effective way to block common-mode noise. The inductor and ferrite bead won't help much which is why common-mode noise is such a pain.

## 4. FB

### Ferrite bead

Blocks higher current. Acts as an inductor (<~10MHz) and resistor (>~50MHz). Rated as XΩ at 100MHz. Helps up to a couple hundred MHz

## 3. Inductor

### Filter inductor

Blocks current. Great for low to mid frequency range (up to ~100MHz). Check datasheet for self-resonant frequency. All inductors have inter-winding capacitance which hurts HF filter performance

## 2. CIN

### Ceramic input capacitor.

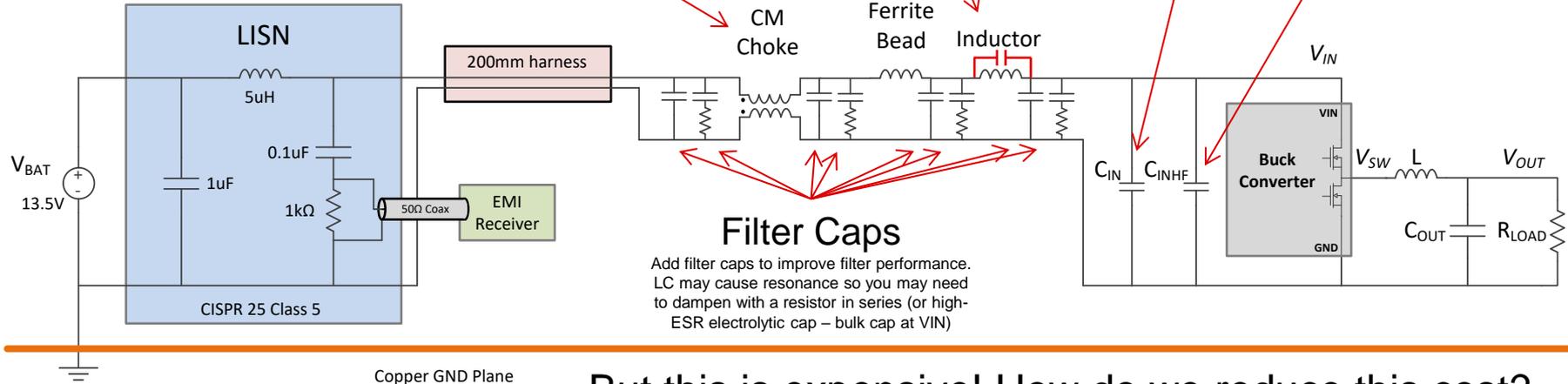
Required for proper operation (see datasheet). Extra CIN helps low frequency EMI by reducing ripple.

## 1. CIN\_HF

### Small ceramic input capacitor.

Place close to IC to minimize loop from VIN to GND. Required in datasheet for proper operation.

## CISPR 25 Class 5 – Conducted EMI Test Setup



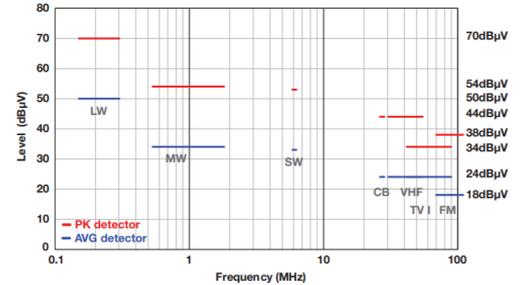
But this is expensive! How do we reduce this cost?

# Where does the noise come from?

**If we know where it comes from, we can optimize for it  
and save money on the filter!**

# Noise sources – low frequency ( $\rightarrow \sim 30\text{MHz}$ )

- Lots of current to fail – differential-mode EMI.
  - VIN ripple fundamental and early harmonics
    - Reduce by increasing input capacitance.
    - Filter with inductor and capacitor. Easy but expensive.



Conducted EMI limits - CISPR25 Class 5

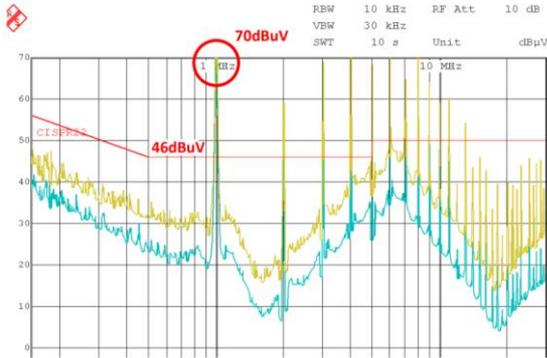


Figure 6. Initial EMI Sweep With CISPR-22 Average Limit Lines

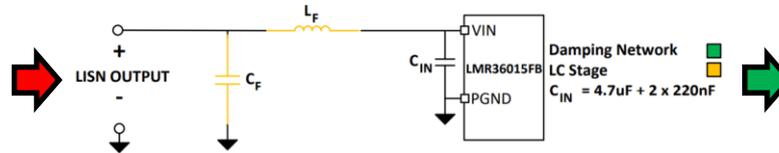


Figure 7. LC Filter Implementation

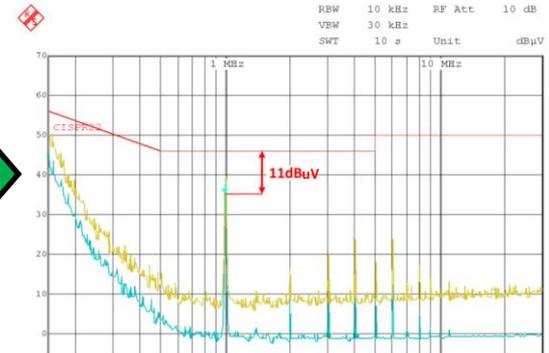


Figure 8. Passing CISPR-22 EMI Limits With a Simple LC Filter

[SNVA859](#) shows how to size a simple LC filter to attenuate low-noise EMI for industrial CISPR22 standards.

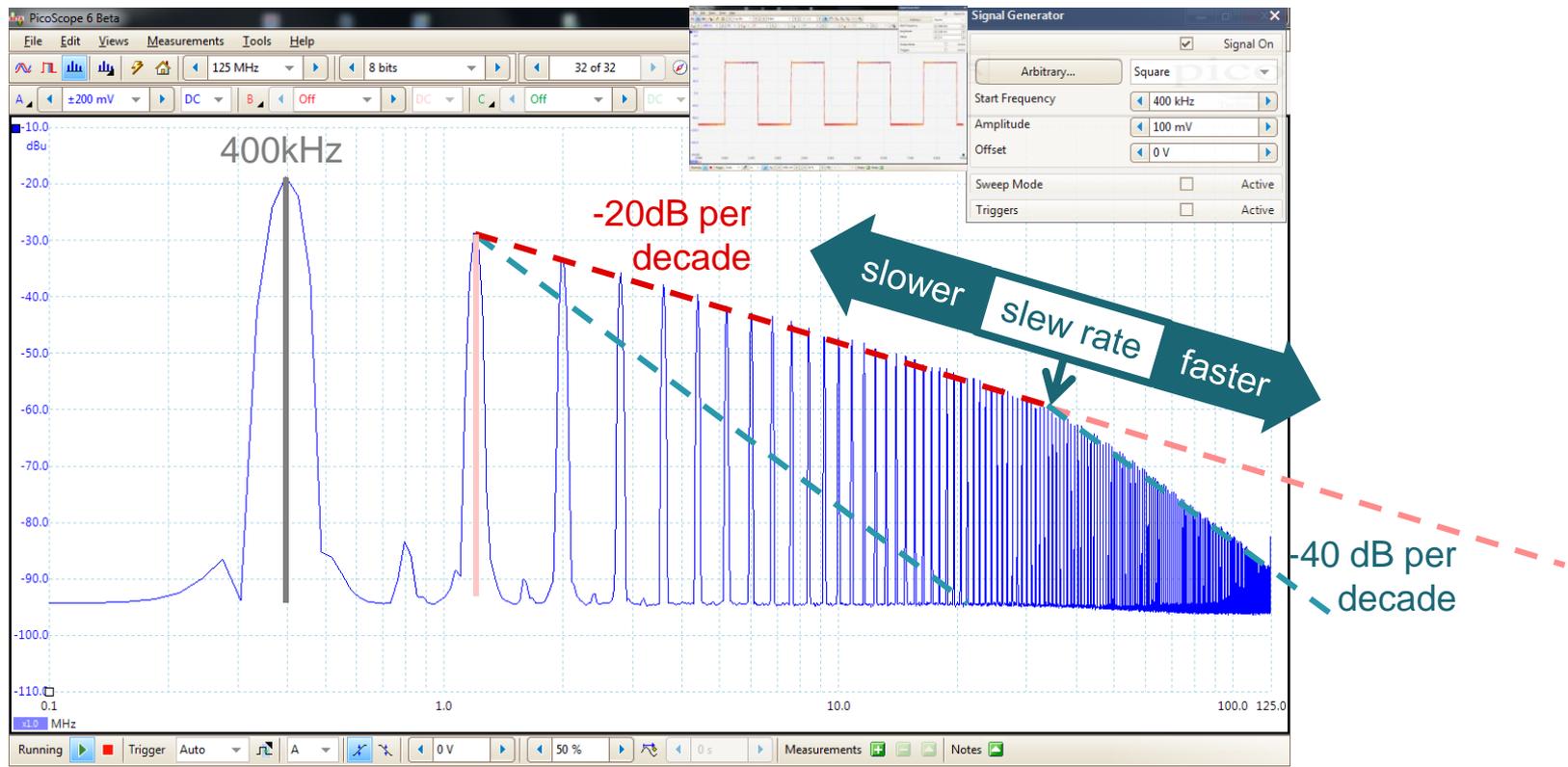
## Noise sources – high frequency (>~30MHz)

- Very little current to fail – SW higher harmonics and SW ringing.
  - Differential mode:
    - Noise goes through inter-winding capacitance of filter inductor
  - Common mode:
    - SW node capacitively coupling to GND plane.
    - BOOT/BST node capacitively coupling to GND plane.
    - SW ring on  $V_{IN}/V_{OUT}$  coupling to GND plane.
- Harder to filter!
  - Is it a differential-mode or common-mode issue?
  - Adding bigger filter inductor probably increases inter-winding capacitance → more high-frequency EMI
  - Where is it coming from?

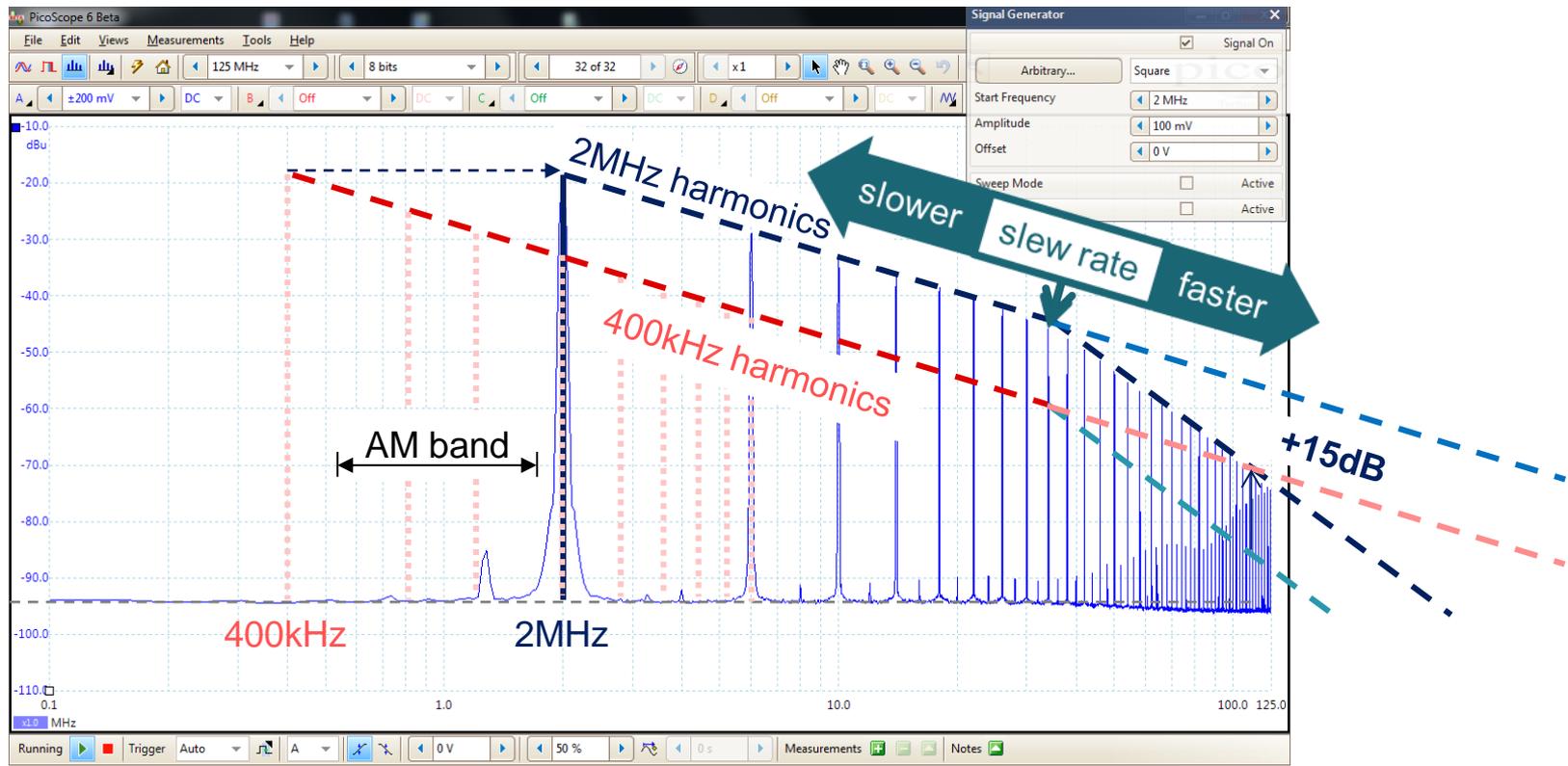
**And to make it harder:**

**400kHz → 2.2MHz**

# 400 kHz square wave spectral density



# 400 kHz switch to 2 MHz



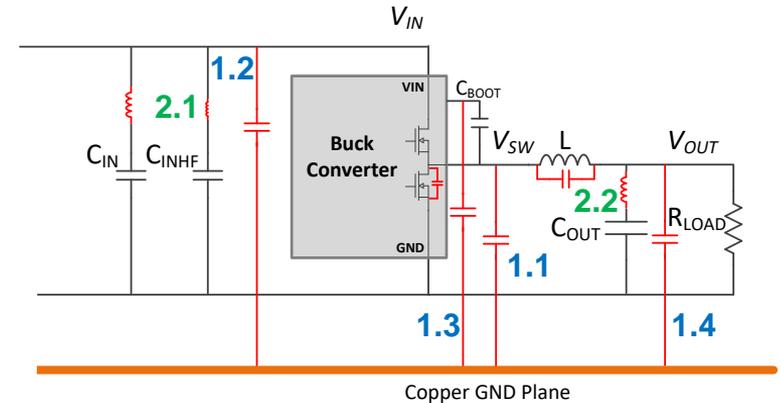
# Layout guidelines

## How to achieve optimal EMI performance

# EMI-optimized layout – two simple rules to reduce noise generation

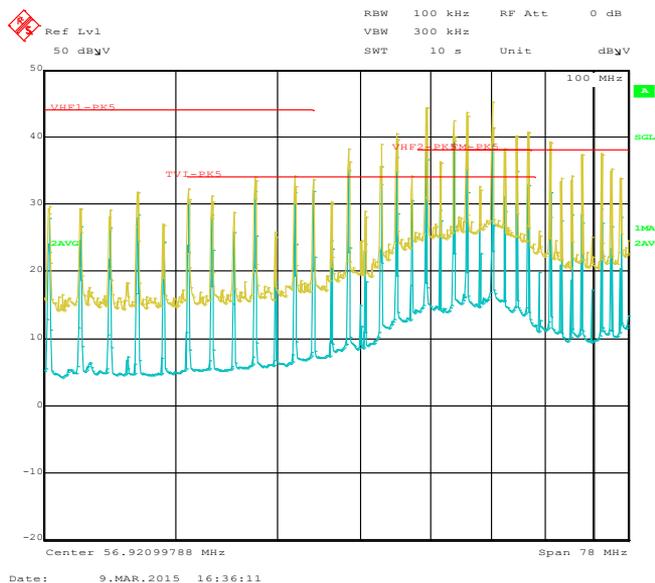
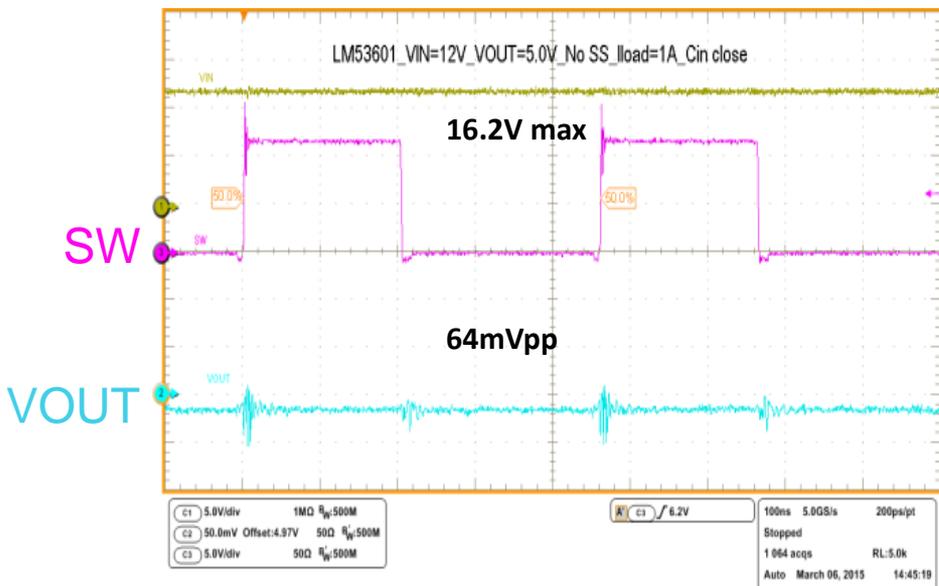
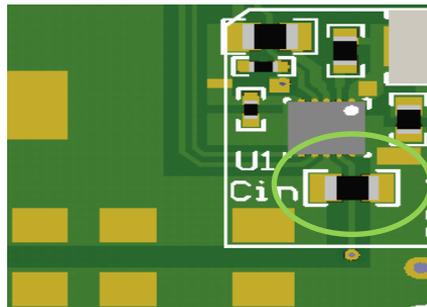
1. Keep high  $dv/dt$  nodes shielded or small.
2. Keep high  $di/dt$  loops small.

- 1.1) SW node size, proximity, lack of shielding  
→ coupling from SW harmonics/ringing
- 1.2) VIN ringing coupling proportional to VIN  
size, proximity, lack of shielding
- 1.3) BOOT/BST pin also noisy
- 1.4) VOUT noise coupling proportional to VOUT  
size and noise on VOUT
- 2.1) CIN loop inductance → ringing
- 2.2) Output capacitance loop through inter-  
winding cap of L



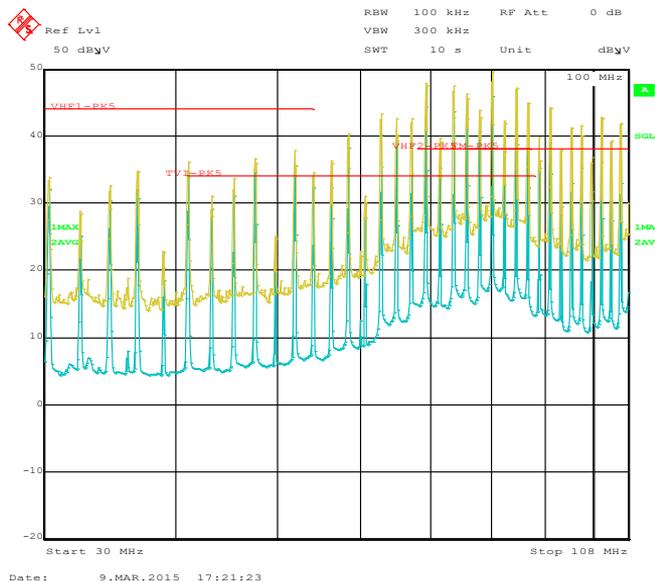
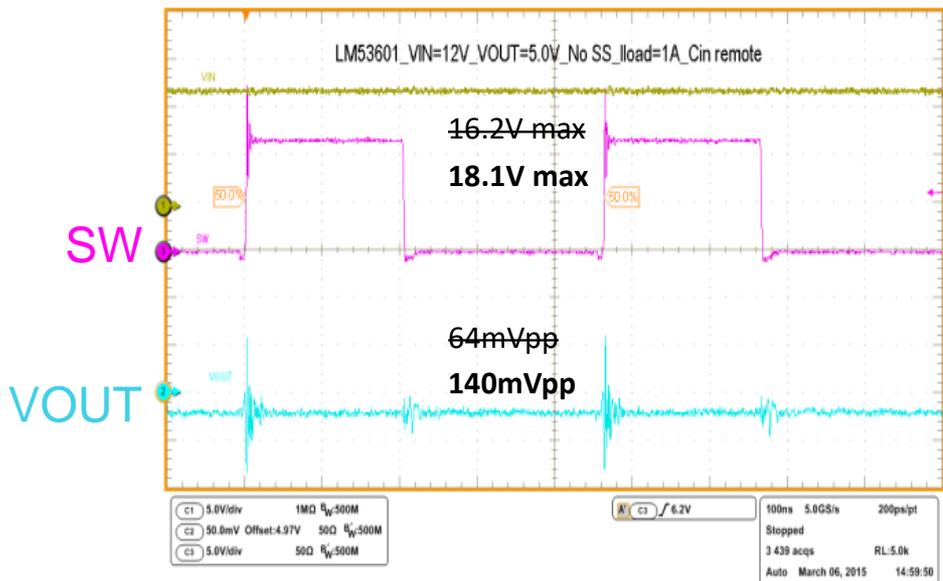
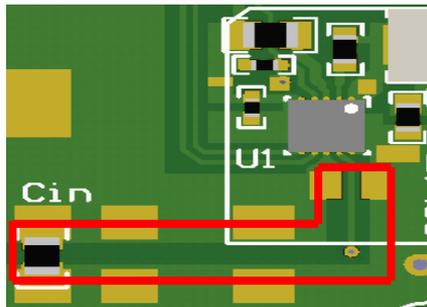
# Critical path area comparison

- Input cap close to IC
- Small input loop, small parasitic inductance

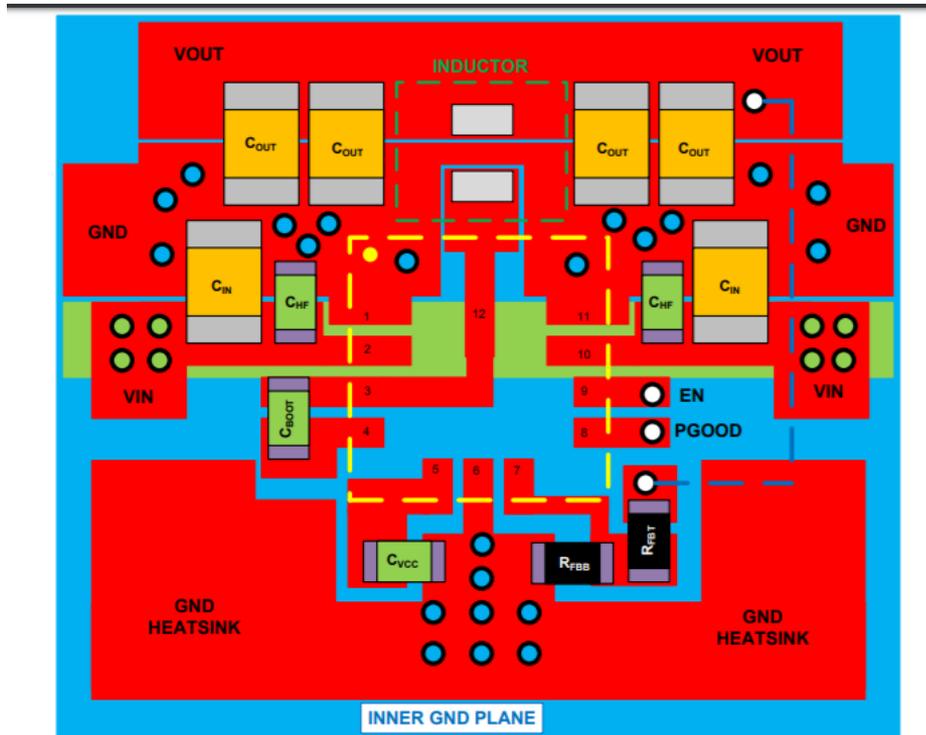


# Critical path area comparison

- Input cap close to IC
- Small input loop, small parasitic inductance

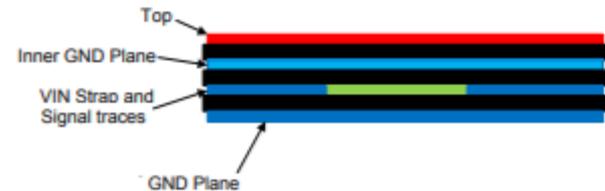


# EMI-optimized layout



GND plane under IC

- Top Trace/Plane 
- Inner GND Plane 
- VIN Strap on Inner Layer 
- VIA to Signal Layer 
- VIA to GND Planes 
- VIA to VIN Strap 
- Trace on Signal Layer 



# But what if we don't have an EMI-optimized layout?

- Reasons we might not have an EMI-optimized layout:
  - Space constraints:
    - Must place circuit into small area or particular shape.
    - Component placement may be less than optimal, far away, bottom-side of board.
  - Thermal considerations:
    - More copper on hot nodes (GND, VIN, SW) will spread heat but more copper on noisy nodes (SW, VIN) will hurt EMI performance.
  - Time constraints:
    - Not enough design time to optimize layout for EMI.
  - Inexperience or lack of attention:
    - It's hard to know and consider everything.
    - Layout issues can happen to anyone.
- What else can we do to improve EMI?

**How do we make this easier?**

**Package, features, external add-ons**

# How to achieve good EMI – part selection and features

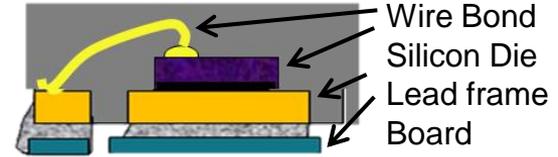
- Package:
  - HotRod™/flip-chip technology.
  - Symmetrical VIN / PGND pins.
  - EMI-friendly pinout.
  - Integrated capacitors.
- Features:
  - Spread spectrum.
  - Advanced frequency modulation.
  - SpSp ripple cancellation.
  - Slew rate control.
  - Active EMI filter.
- Other options:
  - Optimize layout.
  - Flip inductor around 180 degrees.
  - Use small, short, shielded inductor.
  - Snubber.
  - Add more front-end filtering.
  - Add a shield over noisy node.

# HotRod/flip-chip package

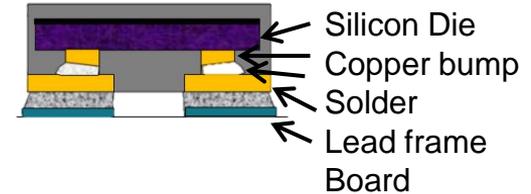
# HotRod/flip-chip package technology

- Bond wire = inductance.
- Inductance  $\rightarrow$  switch node ringing  $\rightarrow$  poor EMI.
- Flip-chip eliminates bond wires  $\rightarrow$  great EMI!

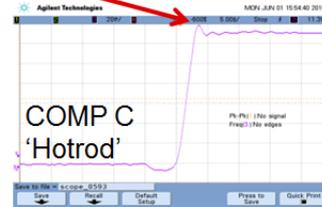
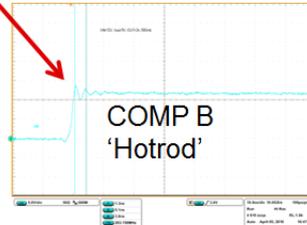
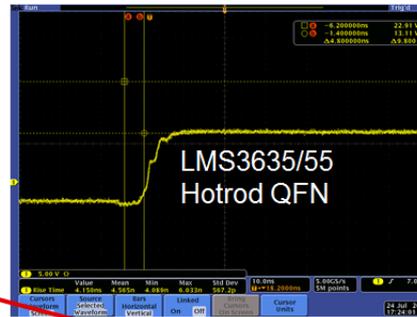
Standard wire bond QFN package



'Hotrod' flip chip on lead frame QFN

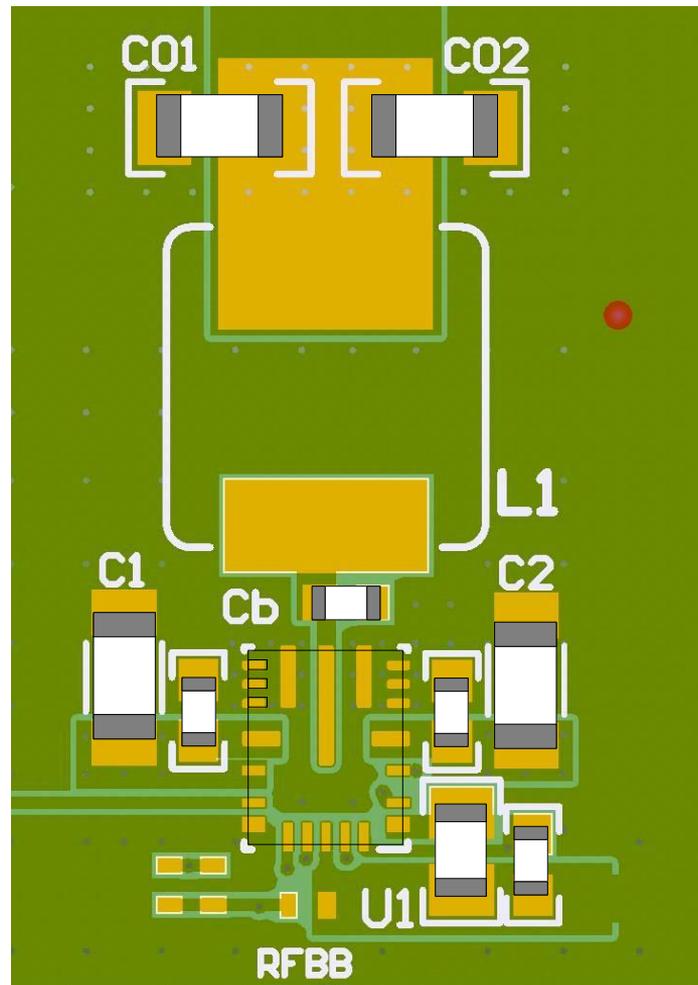
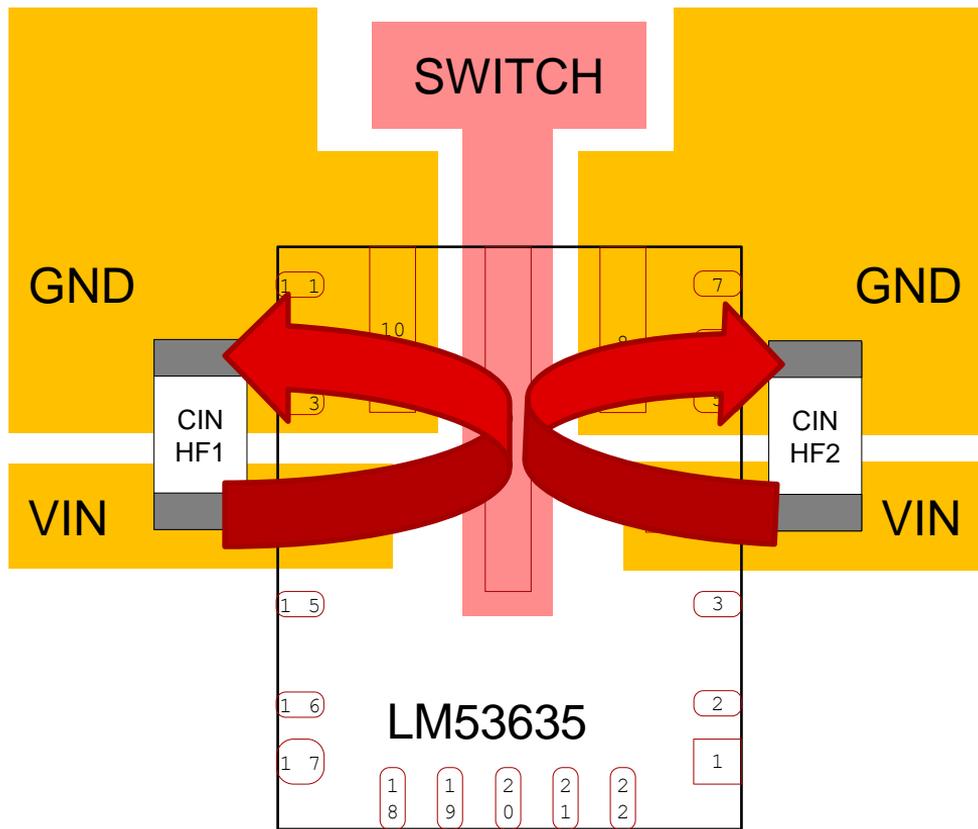


Die is flipped and placed directly onto the lead frame



# Parallel input path

# Parallel input cap placement



# EMI: CIN placement

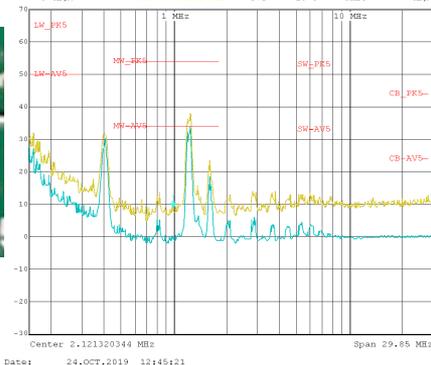
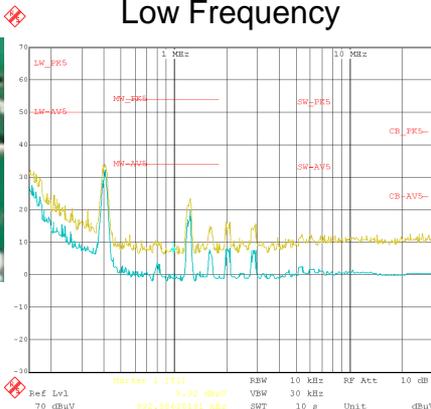


Left: 1x150nF, 2x10uF  
Right: 1x150nF, 2x10uF

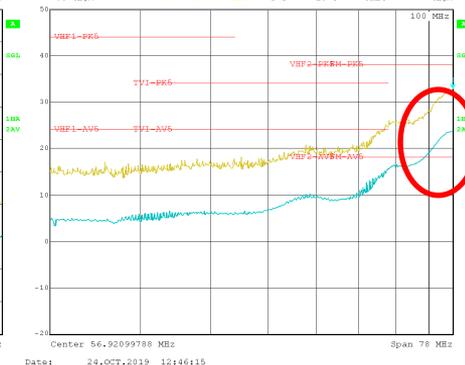
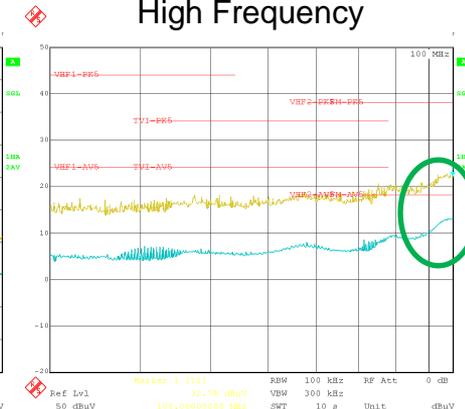


Left: 2x150nF, 4x10uF  
Right: Depopulated

### CISPR 25 Class 5 Low Frequency



### CISPR 25 Class 5 High Frequency



Passing



Failing



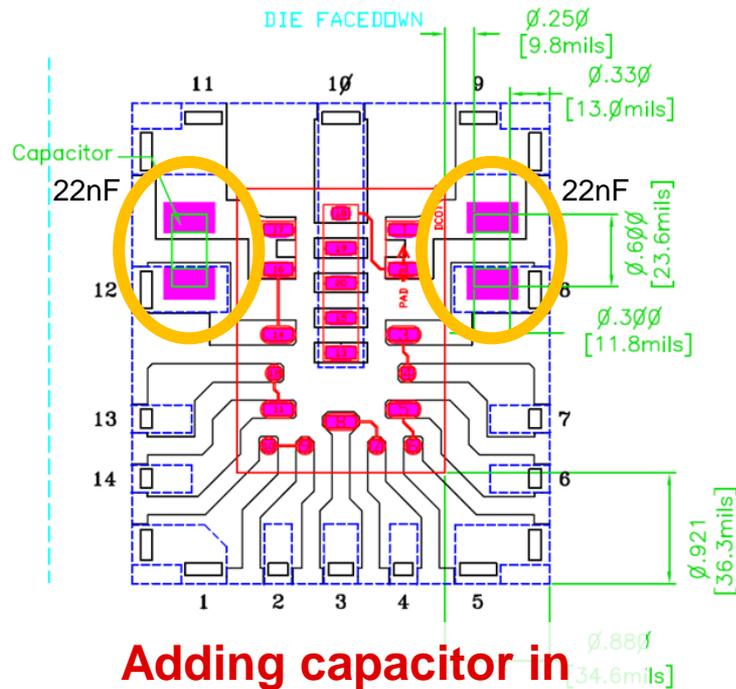
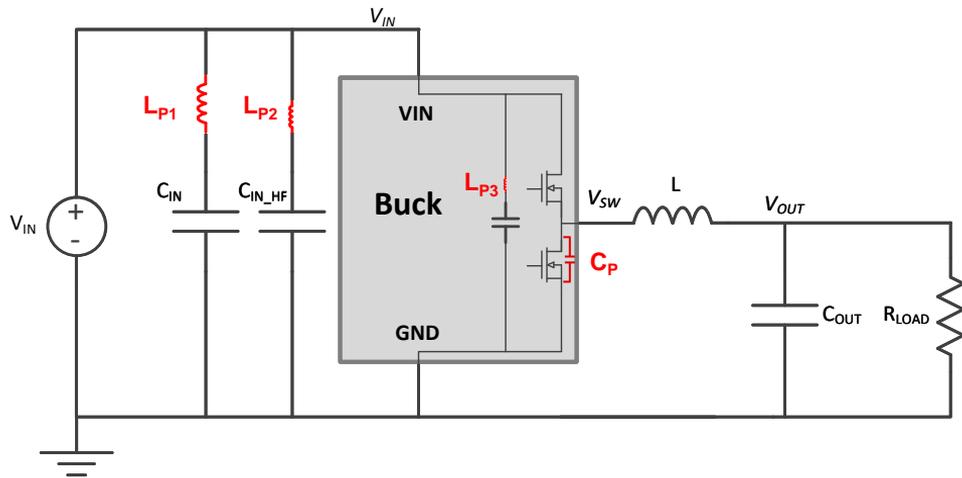
# Integrated capacitors

# Integrated $V_{IN}$ capacitors

Reduce parasitic inductance.

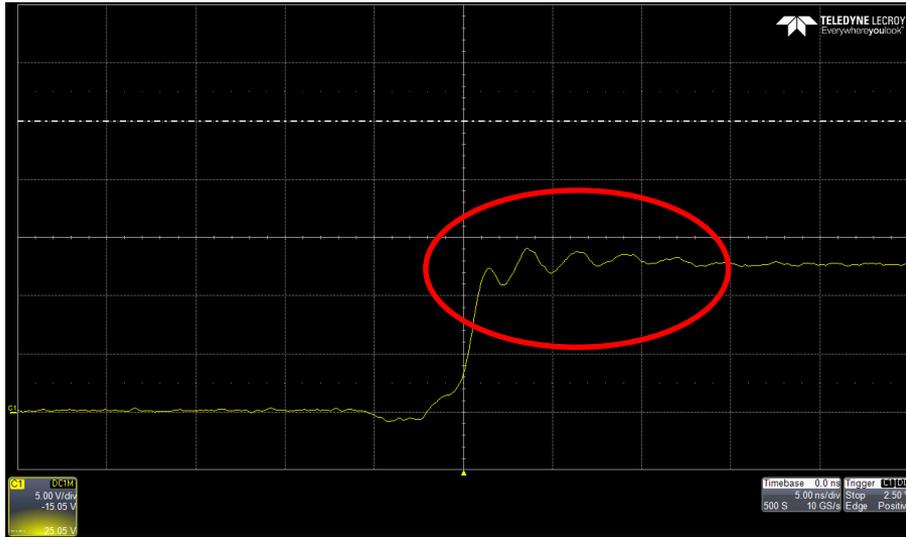
Reduce ringing.

Reduce high-frequency EMI.

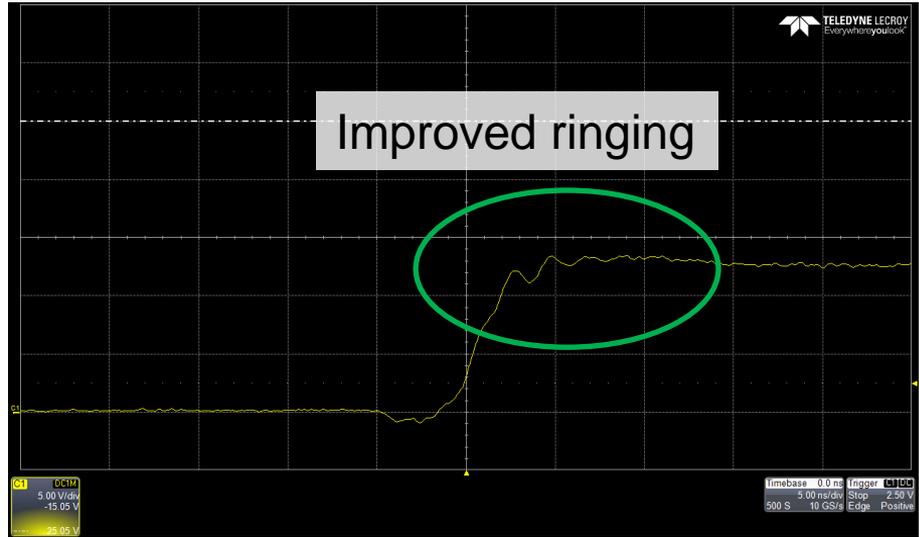


**Adding capacitor in package on leadframe.**

# SW ringing

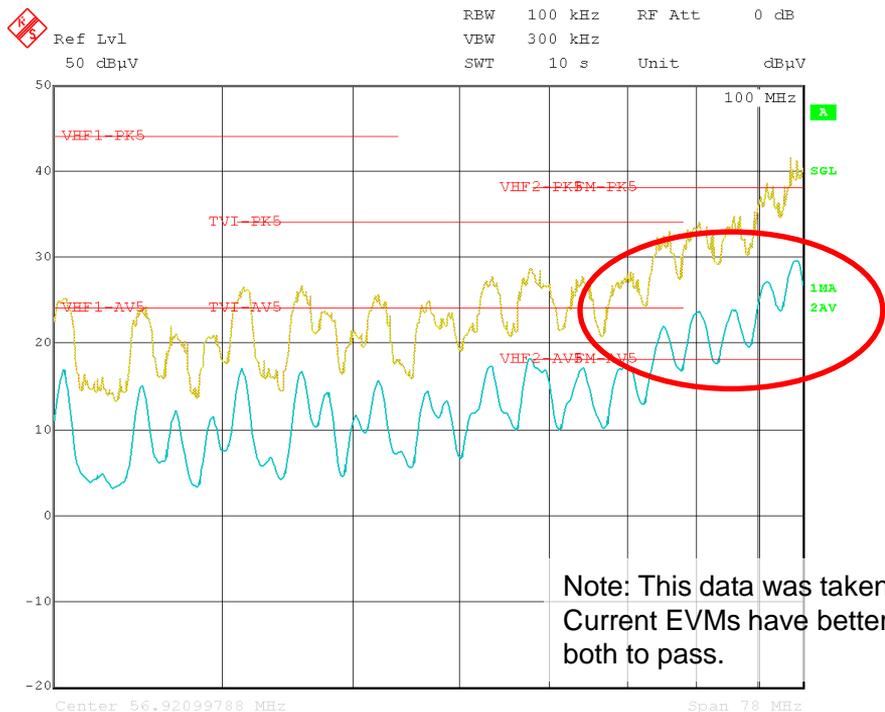


LM62440-Q1 SW ringing

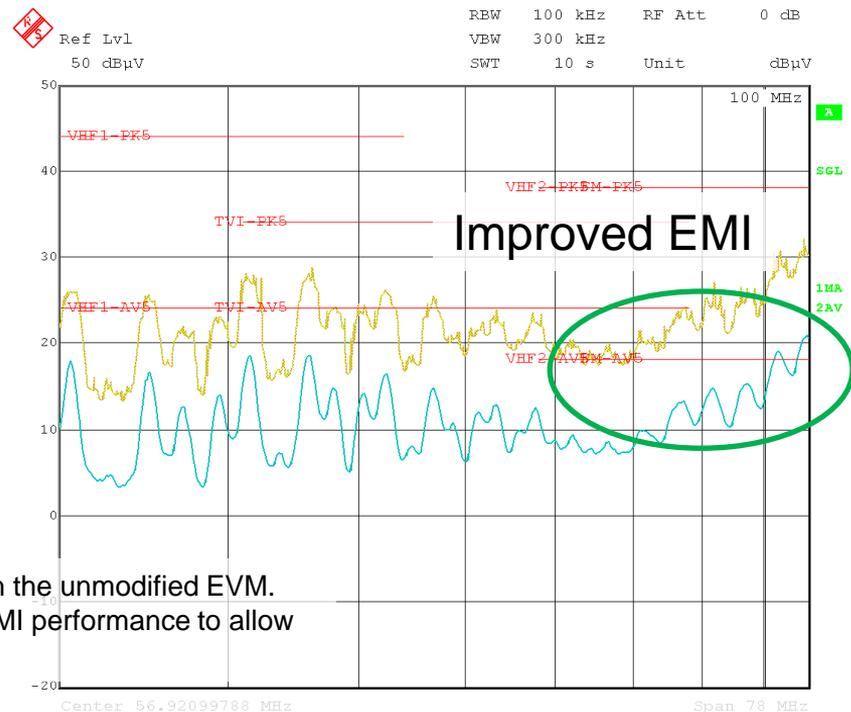


LMQ62440-Q1 SW ringing

# EMI results – identical board and BOM



Note: This data was taken on the unmodified EVM.  
Current EVMs have better EMI performance to allow both to pass.

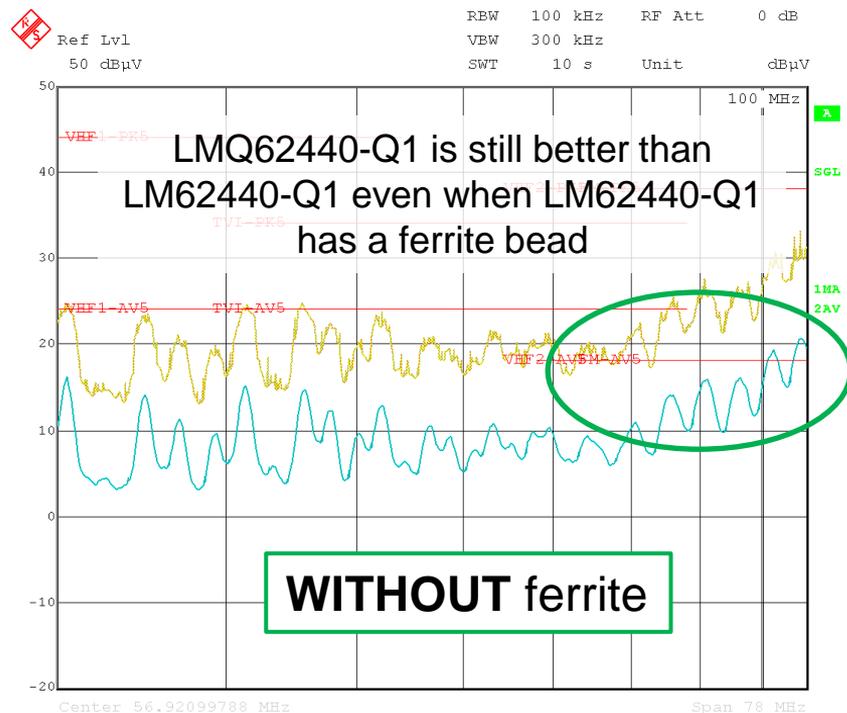
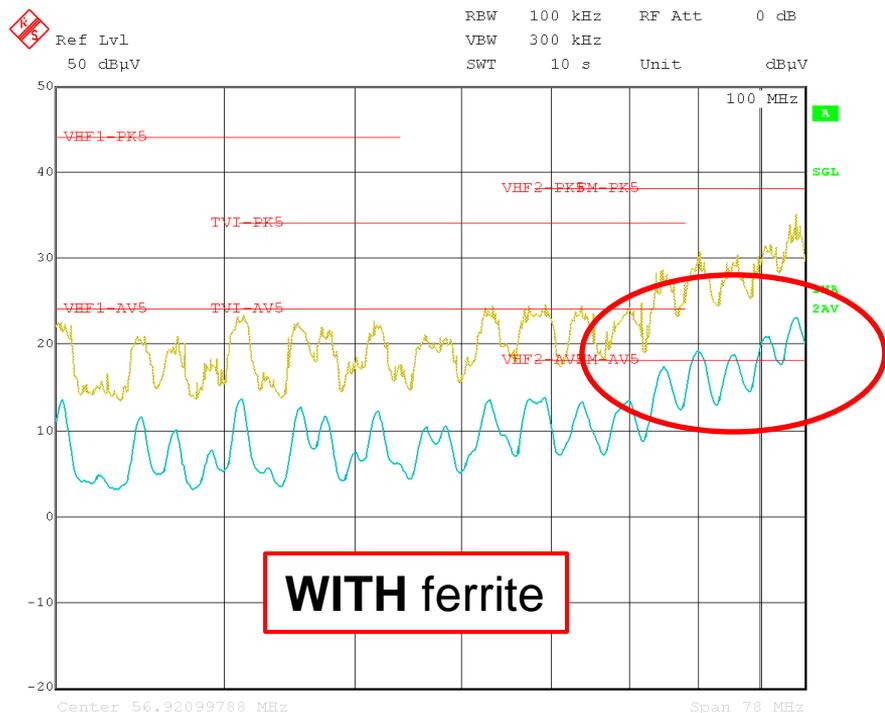


Improved EMI

Center 56.92099788 MHz Span 78 MHz  
Date: 29.OCT.2018 13 **LM62440-Q1 EMI**  
CISPR 25 class 5 conducted high frequency

Center 56.92099788 MHz Span 78 MHz  
Date: 29.OCT.2018 **LMQ62440-Q1 EMI**  
CISPR 25 class 5 conducted high frequency

# EMI – Optimized EMI Filter



# LMQ61460-Q1 / LMQ62440-Q1

## Ultra-low-EMI and highest power density 36-V 2.1-MHz 4-A/6-A

### Features

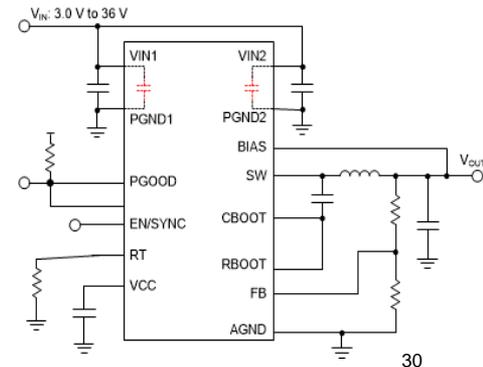
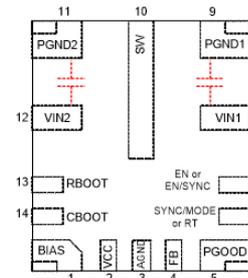
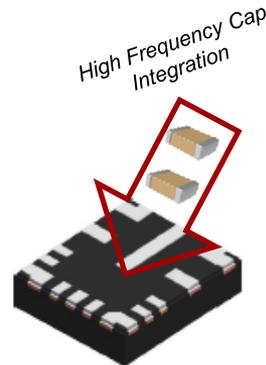
- **Ultra-low EMI:**
  - Dual co-packaged internal bypass capacitors.
  - Spread spectrum & adjustable SW node rise time (Rboot).
  - Tolerant to non-ideal layout.
- **<7  $\mu\text{A}$  standby  $I_Q$**  with BIAS to  $V_{OUT}$  2.1 MHz 13.5 V to 3.3 V no load
- **3.5 mm x 4 mm HotRod™ package; -40°C to 150°C  $T_J$  operation**
- **Pin to pin compatible** with LM614x0-Q1, LM62440-Q1 family
- **Synchronize** to external clock: 200 kHz to 2.2 MHz
- LMQ62440-Q1: pin 6 = MODE/SYNC (4-A DC current max)
  - Pin-select auto mode or FPWM operation; Fixed 2.1 MHz frequency
- LMQ61460-Q1: pin 6 = RT (6-A DC current max)
  - Frequency set by resistor; factory auto mode or FPWM versions
- 3V – 36 V (Abs. Max = 42V) wide input voltage range
- Factory fixed-3.3V, fixed-5 V and adjustable  $V_{OUT}$  versions available

### Applications

- Surround view camera ECU.
- Infotainment head unit.
- Digital cockpit.

### Benefits

- **High efficiency** at heavy load and light load; long standby time with **no load  $I_Q$  as low as 7  $\mu\text{A}$**  and auto mode
- **Low EMI** with co-packaged bypass capacitors; Wettable Flank HotRod™ package; spread spectrum; and adjustable SW node rise time
- **Small solution size** with **3.5 mm x 4 mm Wettable Flank HotRod™ package, 2.2-MHz max frequency and internal HF capacitors**
- **Flexible design options** with Auto Mode (high efficiency at light load and low  $I_Q$ ) or FPWM (fixed frequency for noise reduction)
- **High ambient temp operation** with high efficiency at heavy load and **150°C  $T_{JMAX}$**

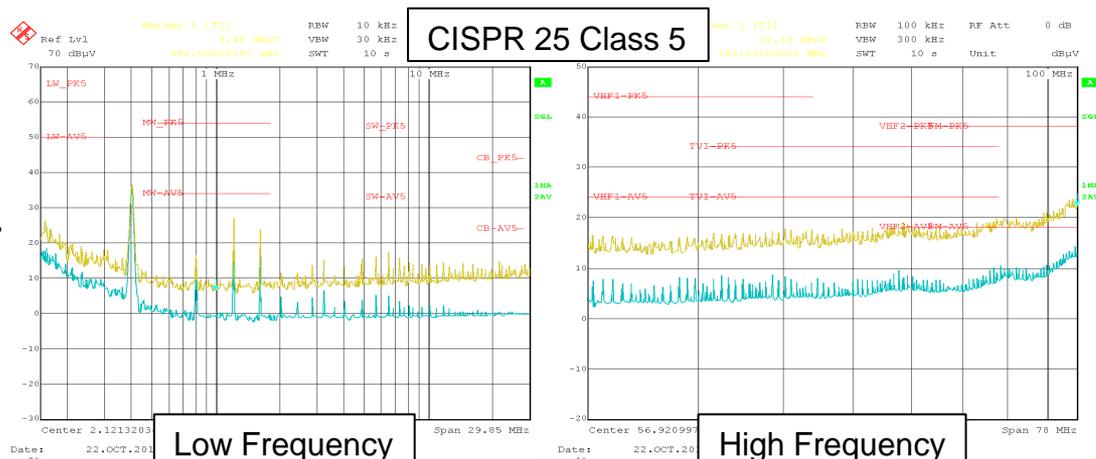


# Spread spectrum

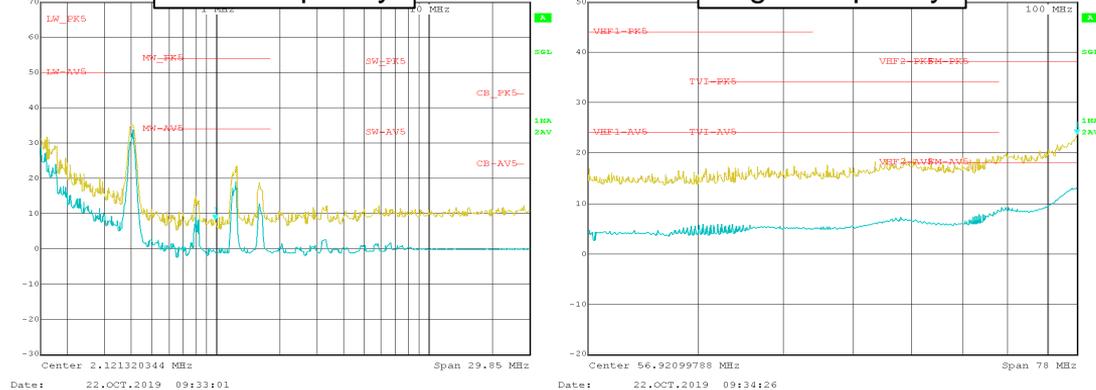
# EMI: spread spectrum effect

$V_{IN} = 12V$   
 $V_{OUT} = 5V$   
 $I_{OUT} = 10A$   
 $F_{SW} = 400kHz$

Spread spectrum OFF

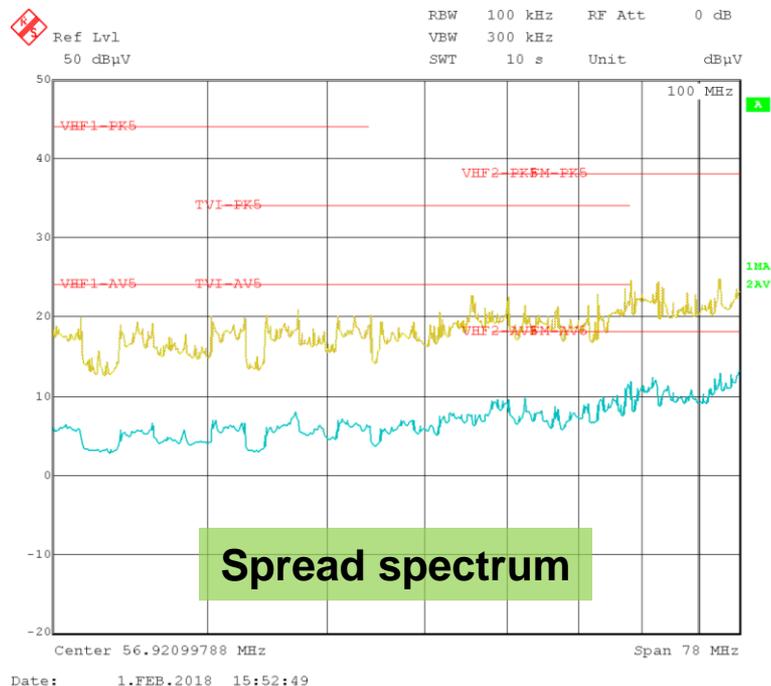
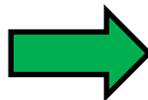
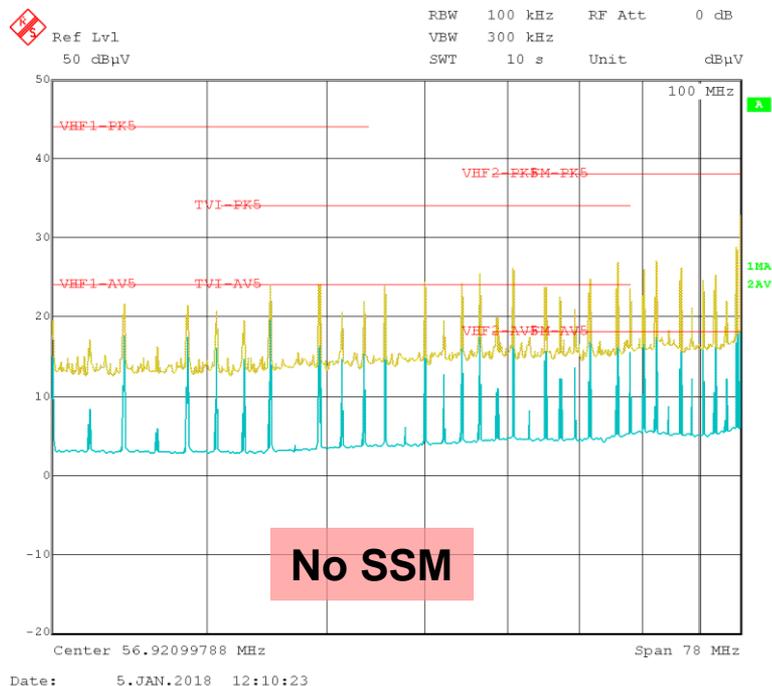


Spread spectrum ON



# Spread spectrum - concept

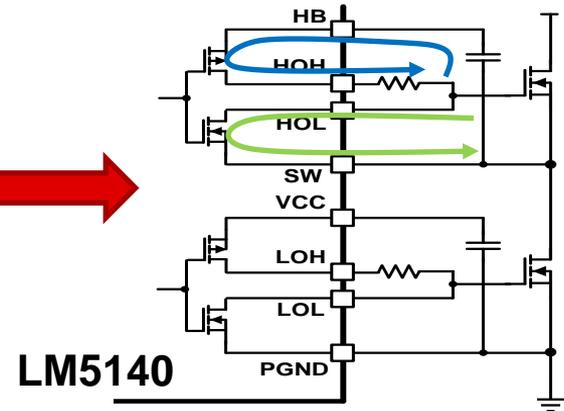
- Dither switching frequency to smooth out the EMI peaks.



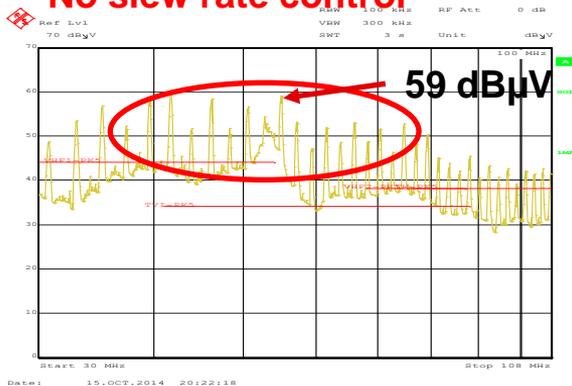
# Slew rate control

# Slew rate control: controller with gate resistors

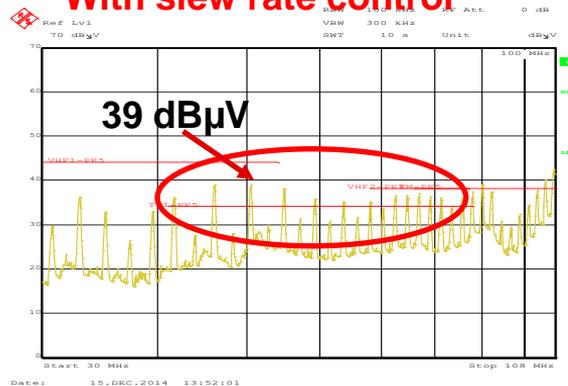
- High and low side FET drivers have separate source and sink pins allowing the turn-on and turn-off times to be independently controlled via series resistors.
- Optimizing gate drive slew rate reduces EMI with ~1% reduction in efficiency (as measured on LM5140 EVM).



## No slew rate control



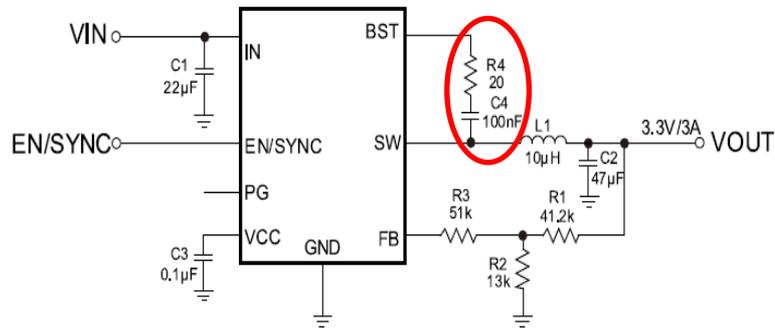
## With slew rate control



Measured on  
LM5140 standard EVM:  
2.2 MHz, 3.3 V/5.0 Vout

# Converter: series RBOOT vs true slew rate control

## TYPICAL APPLICATION



1. Power loss.
2. Not easy to layout.
3. Boot UVLO.
4. Limitations on how much slew.

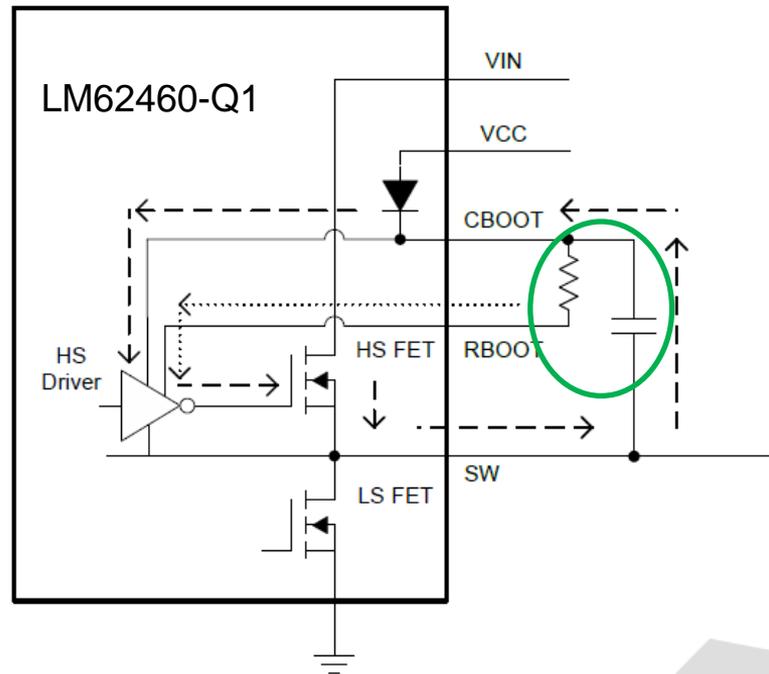


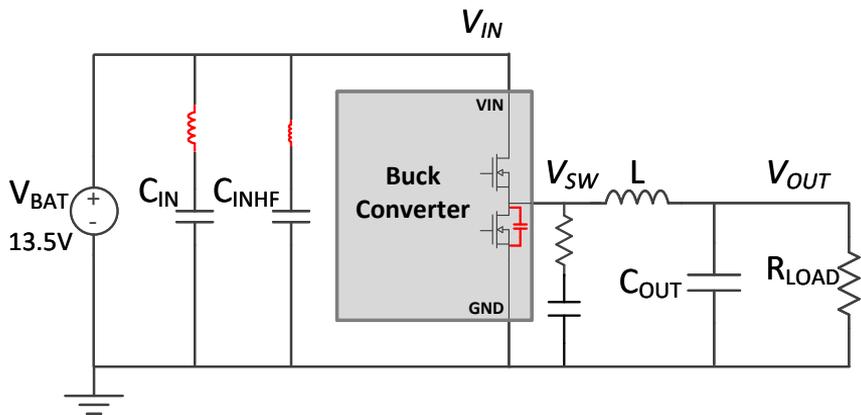
Figure 30. Simplified circuit showing how RBOOT functions.

# Other options:

## Snubber

# Snubber

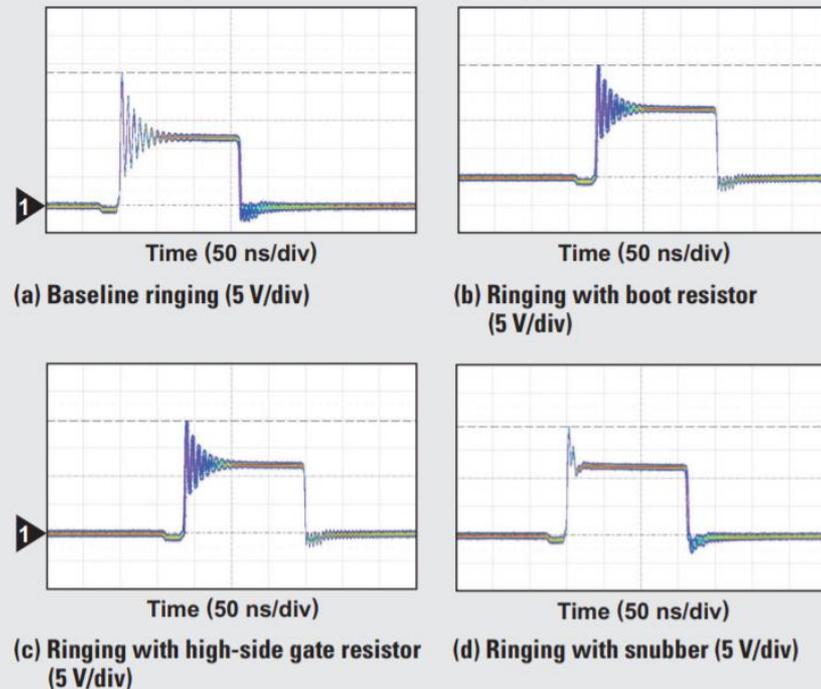
- SW ringing comes from:
  - Parasitic L of input loop (CIN+ to VIN to GND to CIN-) resonating with...
  - Parasitic C from low-side FET
- Snubber absorbs this energy.



Trade EMI performance for efficiency

SLYT465

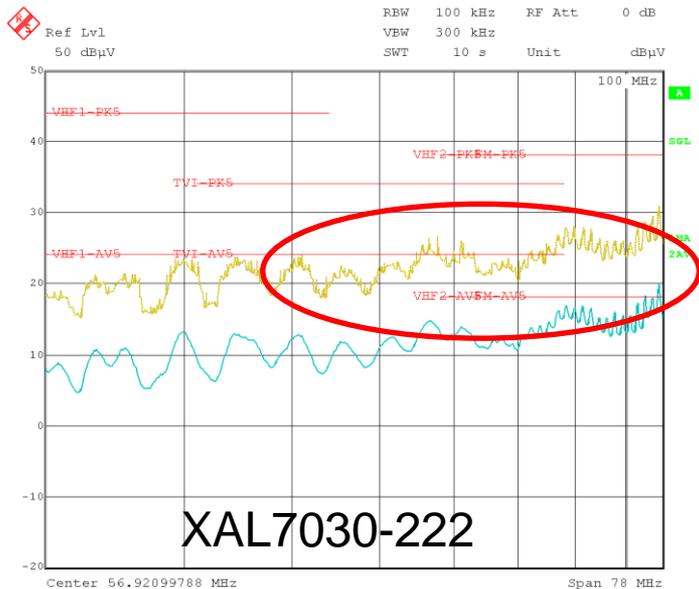
Figure 2. Waveforms of switch-node ringing with 12-V input



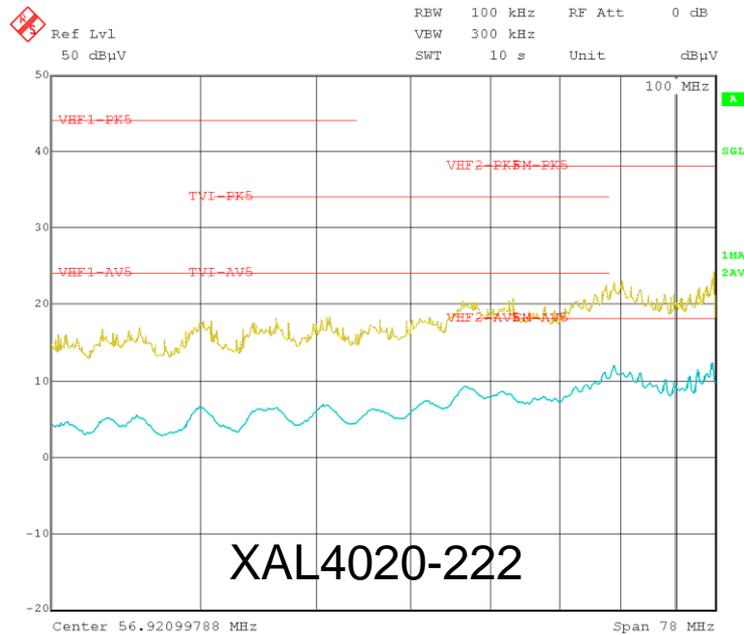
# Inductor selection

# Effect of well shielded small output Inductor

## 30 MHz-108MHz EMI performance comparison



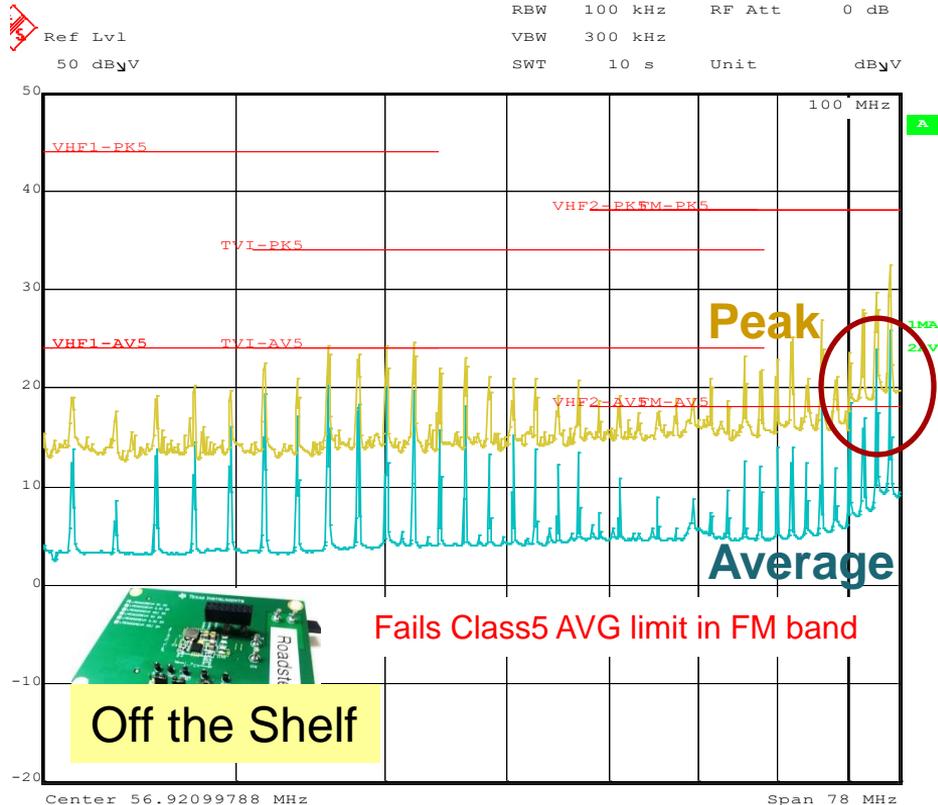
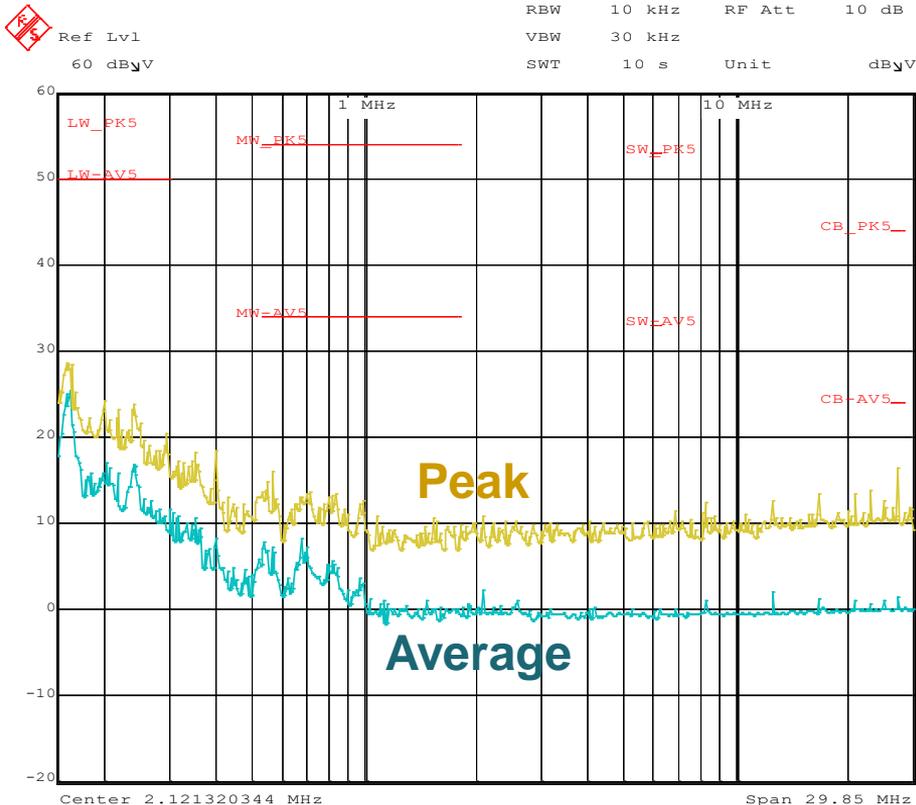
Date: 31.JUL.2018 13:29:44



Date: 31.JUL.2018 13:22:00

# Shield

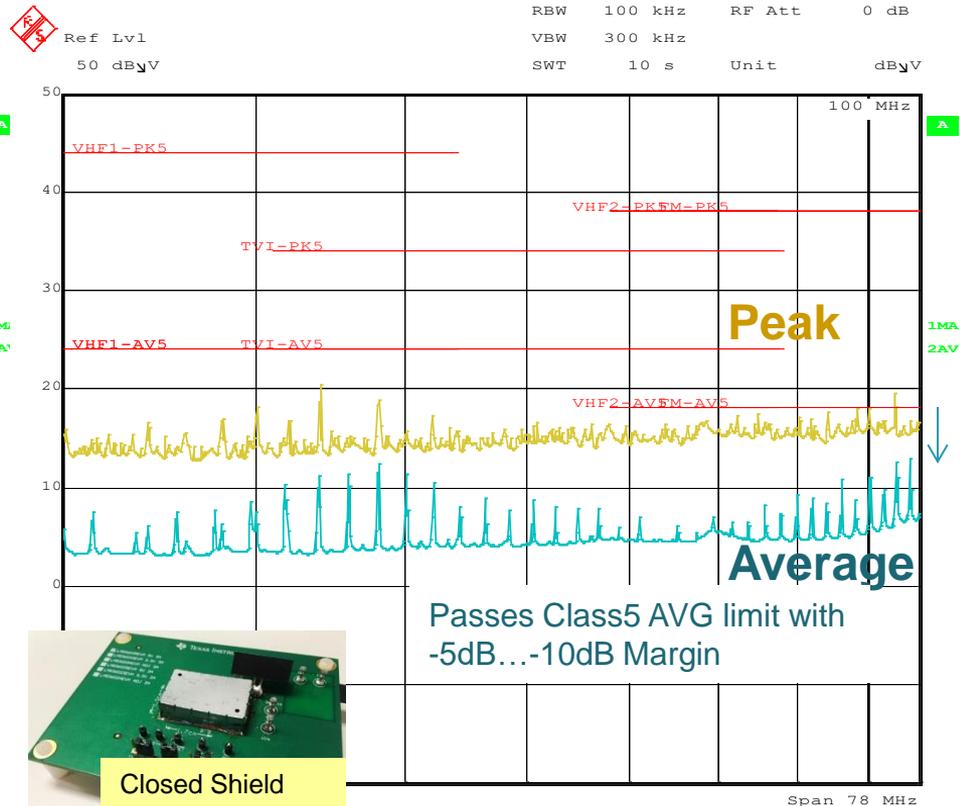
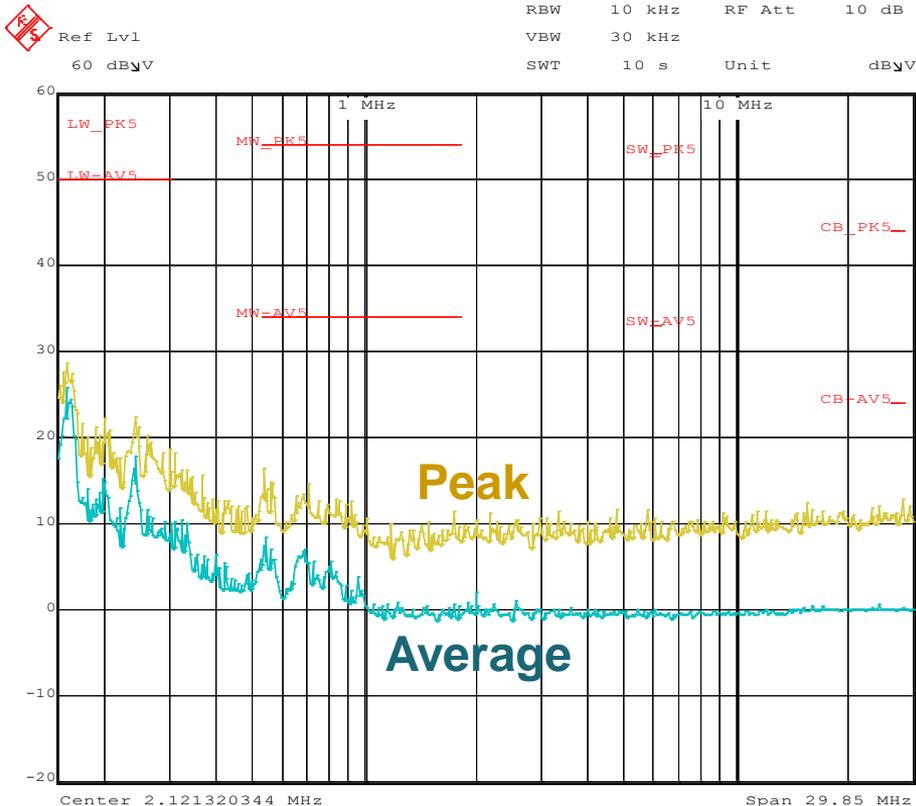
# EMI performance – 13.5Vin / 5Vout @ 3A



Date: 7.APR.2016 15:56:47 150kHz to 30MHz

Date: 7.APR.2016 15:58:39 30MHz to 108MHz 44

# LM53603 EVM - closed shield with metal lid



Date: 7.APR.2016 16:01:44 150kHz to 30MHz

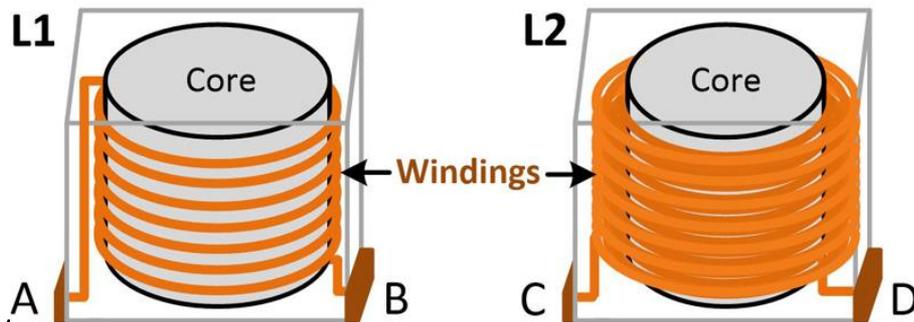
Date: 7.APR.2016 16:00:57 30MHz to 108MHz

# Quick tests and debugging

# Rotate the inductor

- Inductors are not symmetrical.
- One pad connects to SW (noisy).
- Other pad connects to VOUT (quiet).
- Connect the lower winding to the noisy node:
  - Shielded better by the GND plane of the board.
- Connect the inner winding to the noisy node:
  - Shielded by the outer winding.

Real result: LMR33630-Q1 13.5-V<sub>IN</sub>, 5-V<sub>OUT</sub>, 3-A<sub>OUT</sub>, 400-kHz two-layers  
CISPR 25 Class 5: 15 dB $\mu$ V  $\rightarrow$  7 dB $\mu$ V (3 dB $\mu$ V margin  $\rightarrow$  11 dB $\mu$ V margin)



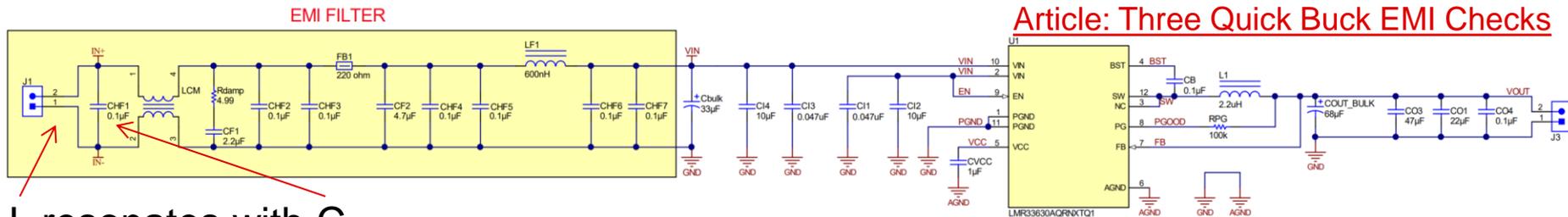
[Article: Three Quick Buck EMI Checks](#)

- But how do you know without cracking open the inductor?
- **Test it, flip it, test it again. Take the better result**



# Remove first CIN cap. resonates with harness

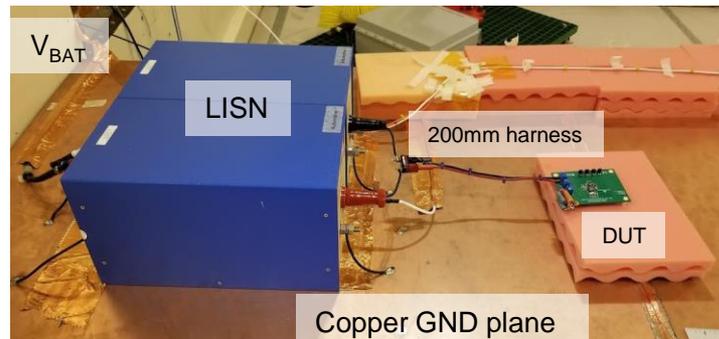
- Test board schematic for LMR33630 showing EMI filter → buck



## L resonates with C

- Parasitic inductance of harness (200mm or 1.5m) resonates with undamped C.
- May cause worse results or may need to be damped with series R (or electrolytic cap).

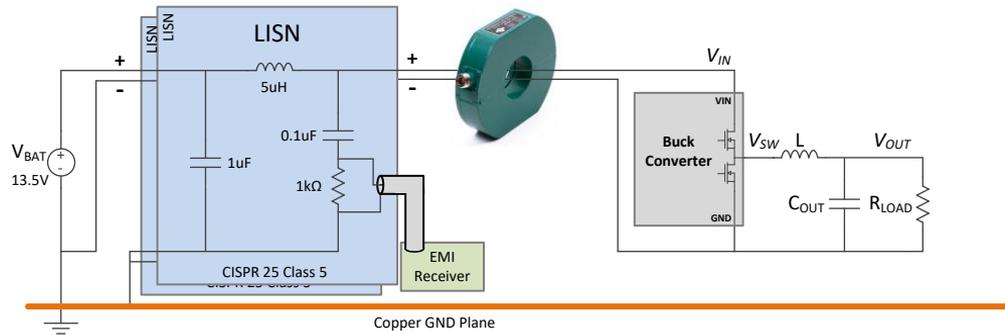
Real result: removing CHF1 resulted in a 3-5 dB $\mu$ V improvement in the FM band.



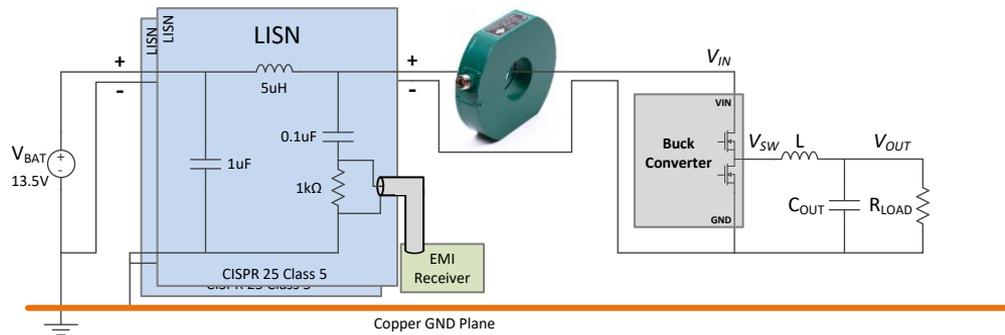
# Current probe around harness

- Place high-frequency current probe around harness to measure noise current.

Place around both wires to measure common-mode current.

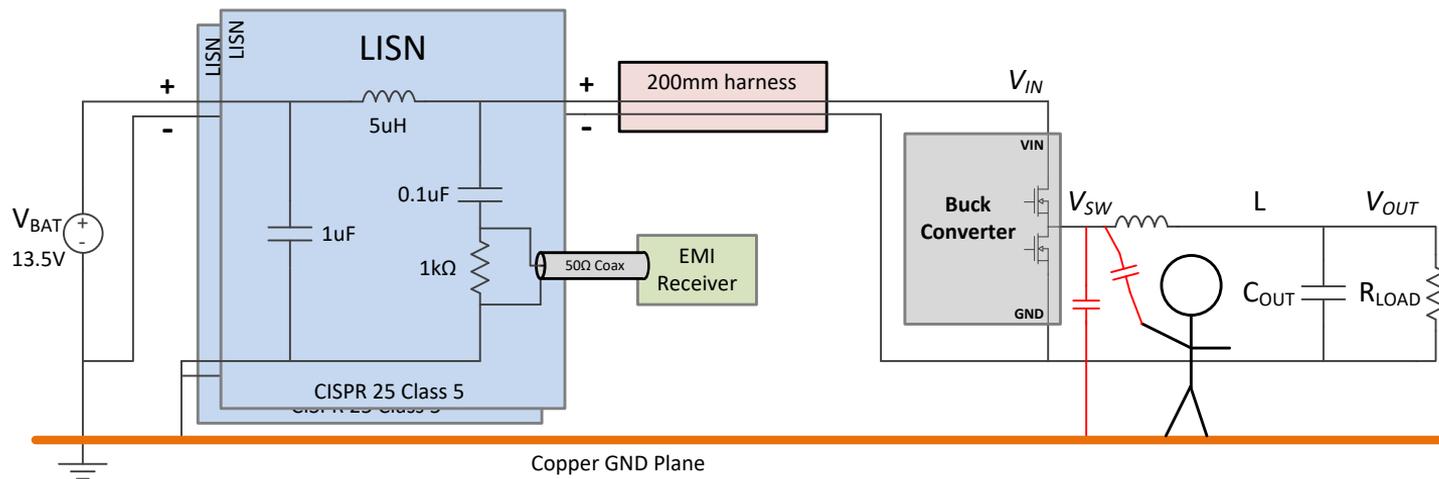


Place around one wire to measure differential-mode current (plus common-mode current).



# Wave hand over the board

- You're adding more capacitance to GND → more capacitively coupled current to GND → more common-mode EMI.
- If there's a large source of common-mode capacitively-coupled EMI, the results will get worse when you place your body close to the board

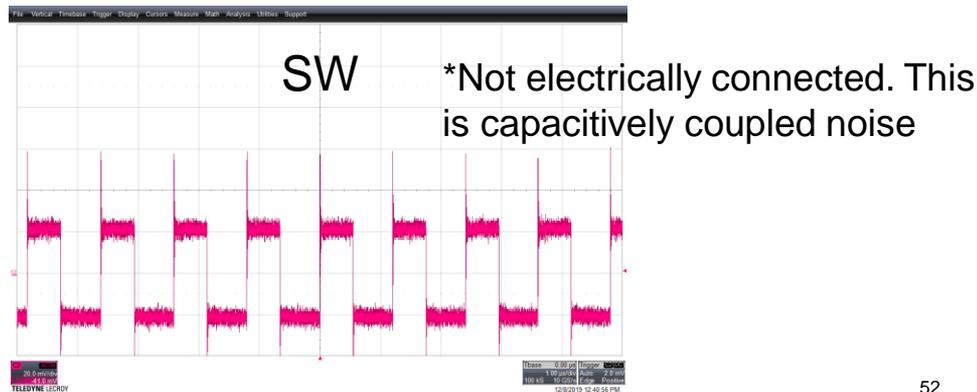
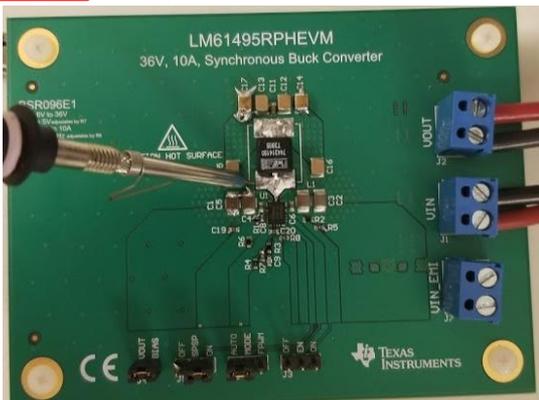
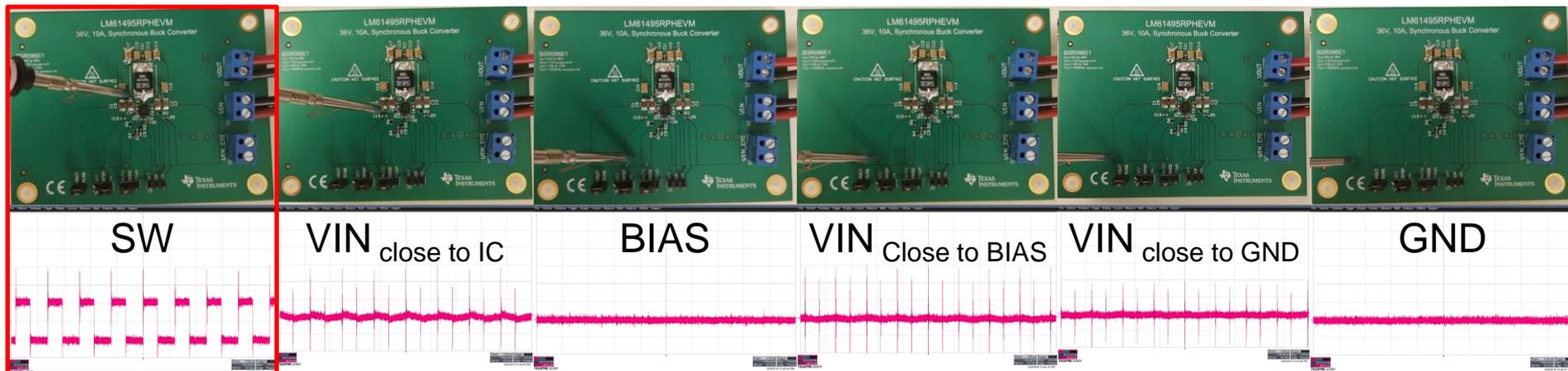


# E-field probe – scope probe over board

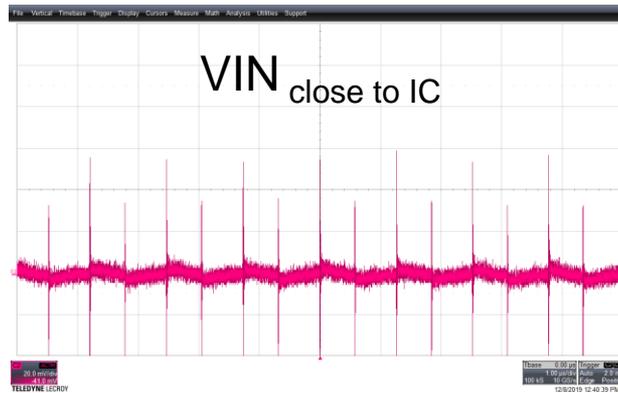
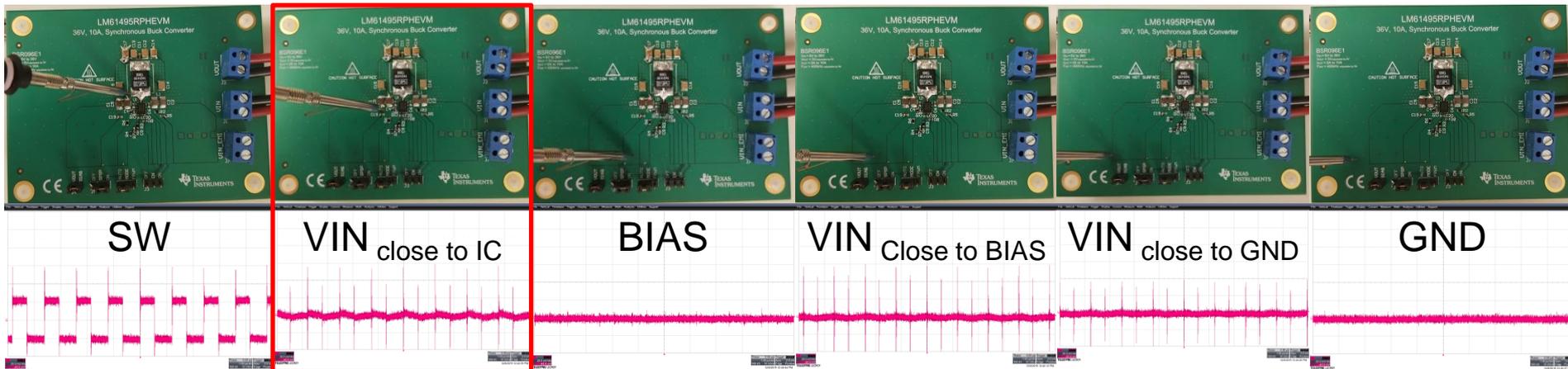
- Place a scope probe tip on the board (not electrically connected).
- Scope will show capacitively coupled noise.



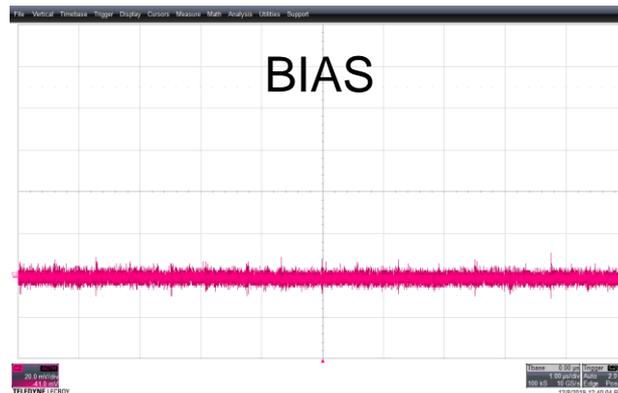
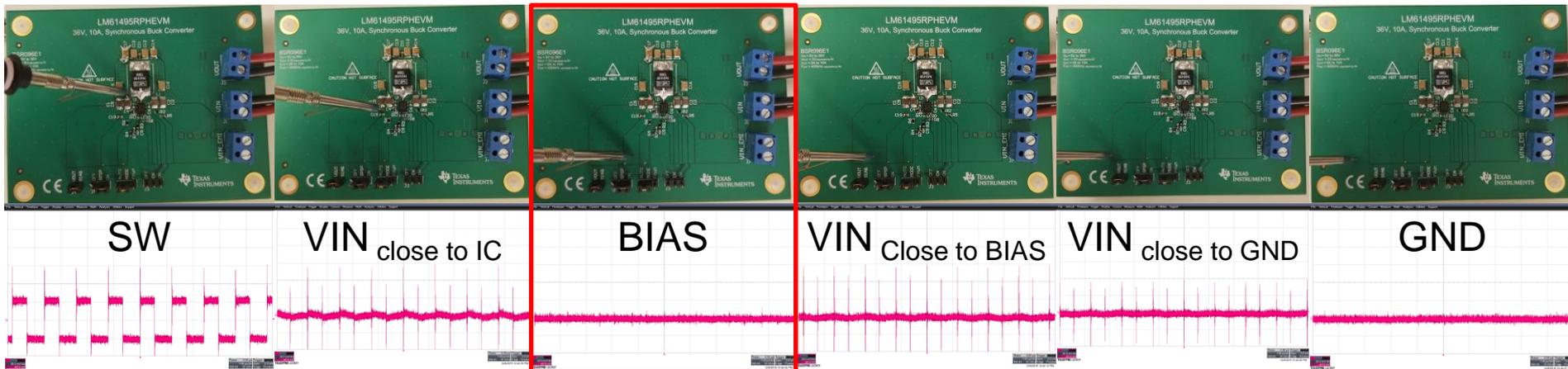
# E-field probe – scope probe over board



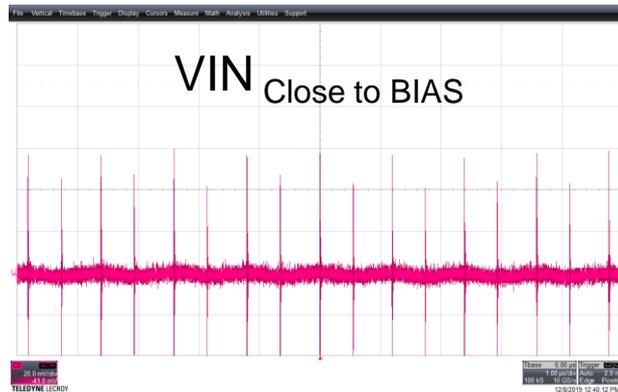
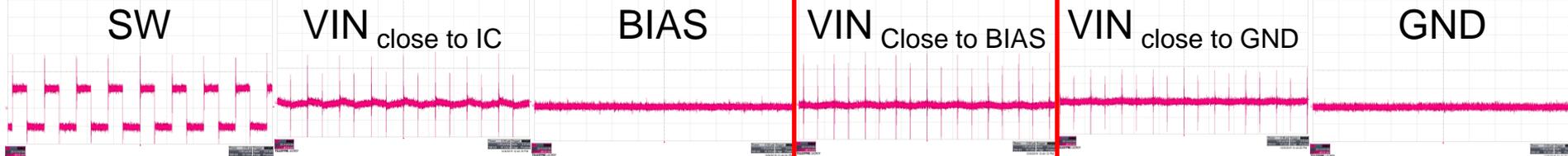
# E-field probe – scope probe over board



# E-field probe – scope probe over board



# E-field probe – scope probe over board



# E-field probe – scope probe over board



SW

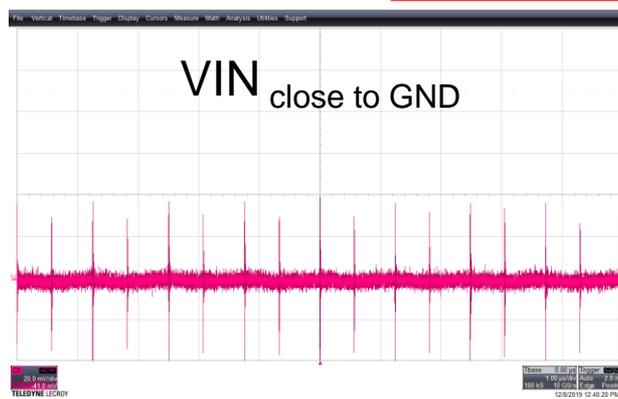
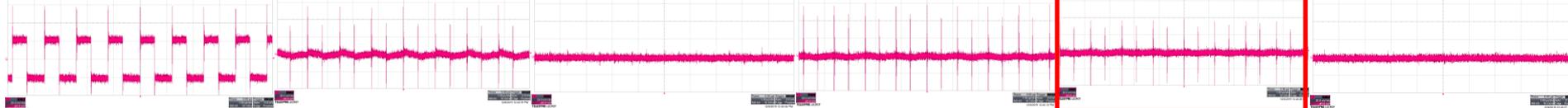
VIN close to IC

BIAS

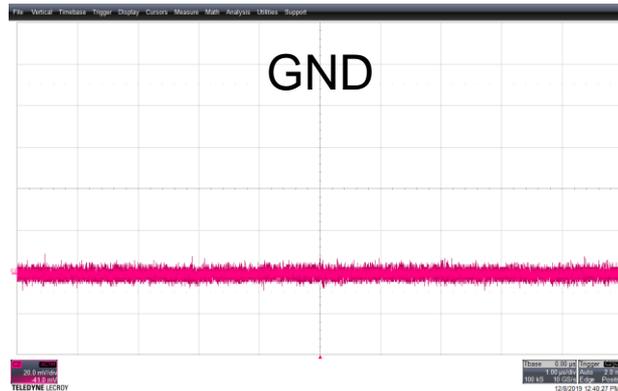
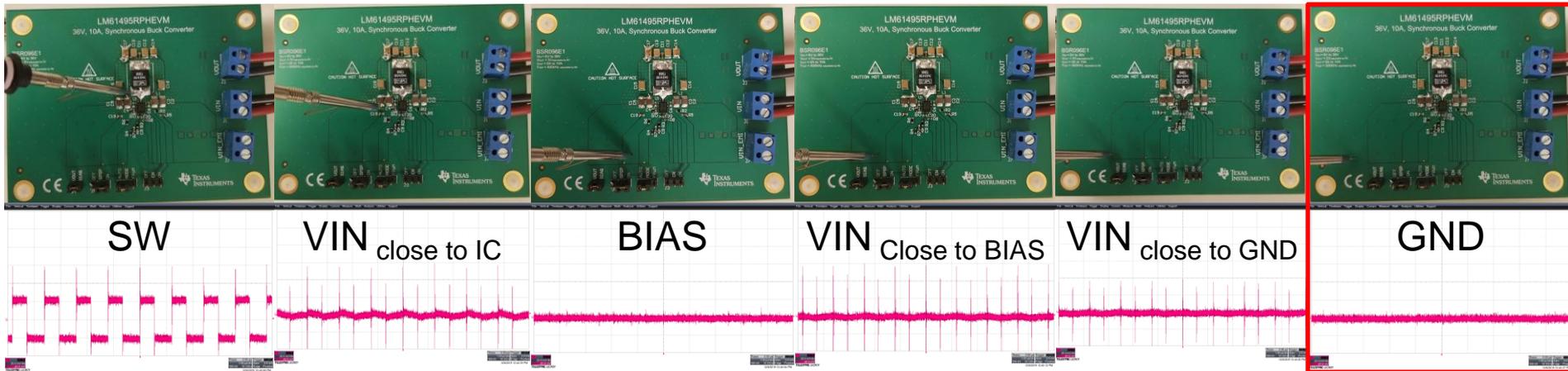
VIN Close to BIAS

VIN close to GND

GND



# E-field probe – scope probe over board



# That's all! Any questions? Topics:

- EMI:
  - What is it?
  - CISPR25
  - Buck EMI
- Package:
  - Hotrod/flip-chip technology
  - Symmetrical VIN/PGND pins
  - EMI-friendly pinout
  - Integrated capacitors
- Features:
  - Spread spectrum
  - Slew rate control
- Other options:
  - Optimize layout
  - Flip inductor around 180 degrees
  - Use small, short, shielded inductor
  - Snubber
  - Use more EMI filter
  - Add a shield over noisy node
- Debugging:
  - Current probe
  - Literal hand waving
  - E-field probe (scope probe)

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